IEEE Xplore Update – Content, Features and Functionality

George Plosker

IEEE Client Services Manager

September 2015

IEEE Advancing Technology for Humanity

IEEE is the world’s largest professional association dedicated to advancing technological innovation and excellence for the benefit of humanity. More than 430,000 members worldwide.

Mission statement
IEEE's core purpose is to foster technological innovation and excellence for the benefit of humanity.

Many programs, projects and initiatives that IEEE has in place to support this mission…

The world's most successful technology leaders & organizations rely on IEEE information

Technology Companies

- 28 of the top 29 Semiconductor companies
- 9 of top 10 Communications Equipment companies
- All top 10 Aerospace companies
- All top 5 Computer Hardware companies
- 9 of top 10 Auto & Truck Manufacturers
- 7 out of top 10 Telecommunications companies

(Forbes Global 2000 Rankings, May 2014)

Universities

- All of the top 100 engineering schools in US
- 98 of the Top 100 Technical Universities Worldwide

(US News and World Report 2014, Times Higher Education Top Technology Universities)

Government

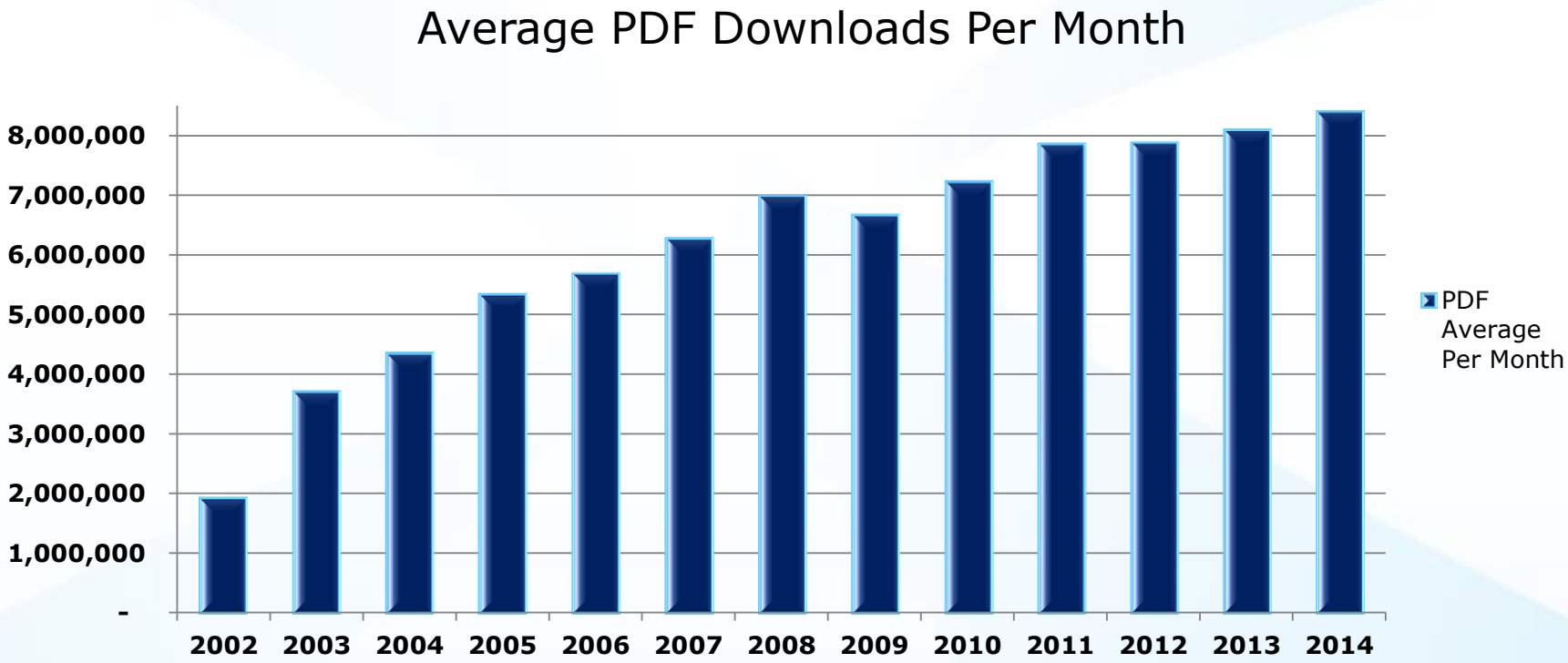
- Defense research and aerospace agencies
- Communications and energy labs
- Patent offices and scientific councils
- Government R&D centers in North America, Europe, Asia and the Middle East

IEEE

All they all use it more & more each year!

Over 8.5 million downloads per month from IEEE *Xplore*

from over 3 million unique users



2014 Milestone: Over 100 million total document downloads!

Source: IEEE *Xplore* Internal Usage Stats

IEEE

Countries that lead the world in downloads from IEEE *Xplore*

- #1 China 
- #2 USA 
- #3 India 
- #4 Taiwan 
- #5 Korea 

Data year end 2014

IEEE

Why do they all rely on IEEE information?

IEEE quality makes an impact

Thomson Reuters Journal Citation Reports® by Impact Factor

IEEE publishes:

- **18 of the top 20** journals in Electrical and Electronic Engineering
- **18 of the top 20** journals in Telecommunications
- **8 of the top 10** journals in Computer Science, Hardware & Architecture
- **7 of the top 10** journals in Cybernetics
- **3 of the top 5** journals in Automation & Control Systems
- **3 of the top 5** journals in Artificial Intelligence
- **2 of the top 5** journals in Robotics

The Thomson Reuters Journal Citation Reports presents quantifiable statistical data that provides a systematic, objective way to evaluate the world's leading journals.

Based on the 2014 study released June 2015

More info: www.ieee.org/citations

IEEE

IEEE quality makes an impact

Thomson Reuters Journal Citation Reports® by Impact Factor

IEEE journals are:

- **# 1** in Automation and Control
- **# 1** in Artificial Intelligence
- **# 1** in Computer Hardware
- **# 1** in Cybernetics
- **# 1** in Electrical Engineering
- **# 1** in Information Systems
- **# 1** in Measurement
- **# 1** in Theory and Methods
- **# 1** in Telecommunications
- **# 2** in Aerospace Engineering
- **# 2** in Robotics

Based on the 2014 study released June 2015

The Thomson Reuters Journal Citation Reports presents quantifiable statistical data that provides a systematic, objective way to evaluate the world's leading journals.

IEEE

Stay current with IEEE

The technology landscape is constantly evolving and so are IEEE publications.

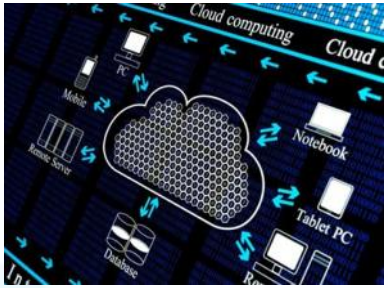
Each year, IEEE introduces new journals, conferences, and standards to address growing areas of research, such as Cloud Computing, Big Data, Smart Grid technology, Internet of Things and others.

- New journal and magazine titles
- New conferences titles
- New and revised standards
- New eBooks and eLearning titles
- New tools to discover them all

IEEE

New IEEE Journals in 2014

- *IEEE **Cloud Computing***
- *IEEE **Internet of Things** Journal*
- *IEEE Trans. on **Computational Social Systems***
- *IEEE Trans. on **Control of Network Systems***
- *IEEE **Electrification** Magazine*
- *IEEE Trans. on **Network Science and Engineering***
- *IEEE **Power Electronics** Magazine*
- *IEEE/CAA Journal of **Automatica Sinica***



2003 – 2013: >50 new journals added

IEEE

New IEEE Journals Coming in 2015

- *IEEE Trans. on* ***Big Data***
- *IEEE Trans. on* ***Transportation Electrification***
- *IEEE Trans. on* ***Cognitive Communications and Networking***
- *IEEE Trans. on* ***Computational Imaging***
- *IEEE Trans. on* ***Molecular, Biological, and Multi-Scale Communications***
- *IEEE Trans.* ***on Multi-Scale Computing Systems***
- *IEEE Trans. on* ***Signal and Information Processing over Networks***
- *IEEE* ***Systems, Man, and Cybernetics*** *Magazine*

For a complete title listing, to go: http://ieeexplore.ieee.org/xpl/opacjrn.jsp

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IEEE Conferences leading-edge content

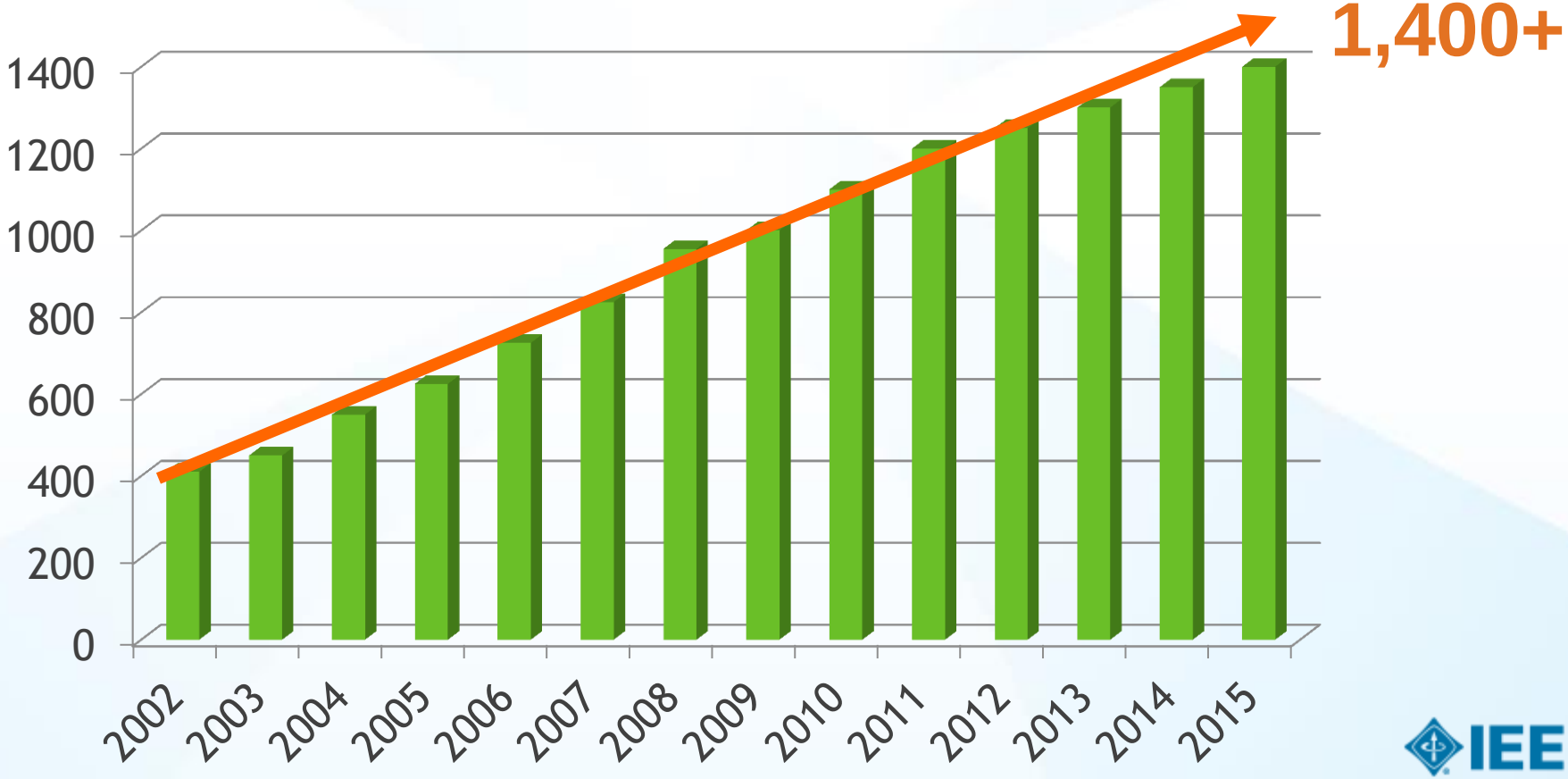
This year the IEEE will publish more than 1,400 leading-edge conference proceedings, which are recognized by academia and industry worldwide as the most vital collection of consolidated published papers in electrical engineering, computer science, and related fields.

- **Breadth of content:** papers on topics from grid computing to wireless communications
- **The latest research**: often published before other leading journals
- **Unequaled depth**: 2.1 million conference papers are available and more than 1,400 conference proceedings titles are published each year
- **Quality of content:** papers authored by innovators of today's top emerging technologies. Most IEEE conferences follow a paper-selection process and many have peer-review procedures

IEEE

The IEEE conference collection continues to grow

Now over 1,400 annual conferences.
Over 2.5 million total papers.



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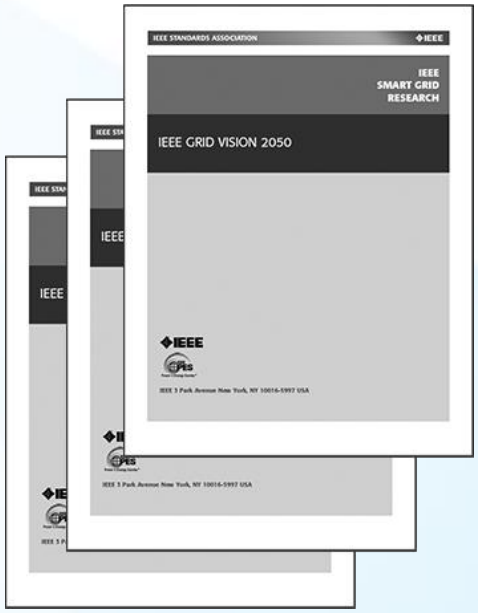
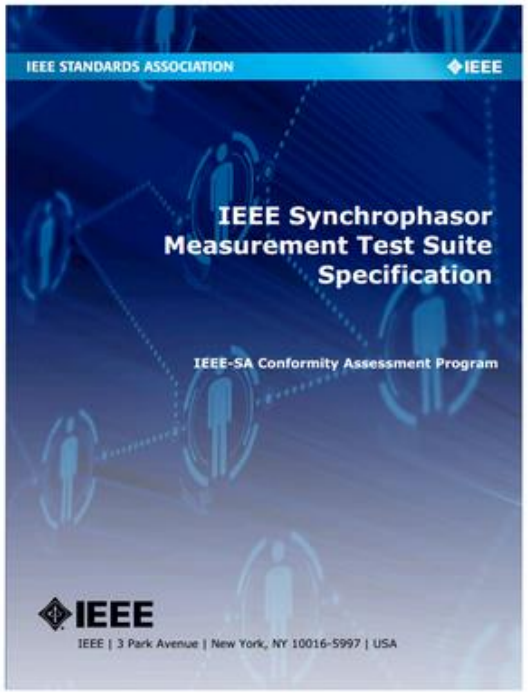
IEEE Smart Grid Research

- A collaborative effort that leverages the work of over 100 industry experts and pioneers in the field to share a view of the future of smart grid as far as 2030 and beyond. These insights are essential to business planning, research, and reference.
- It provides detailed long-term and short-term projections of smart grid industry evolution, technology challenges and opportunities, and areas requiring additional research to help you prepare for what is to come.
- Focused on five technology sectors:
  - — Power, Computing, Communications, Control Systems, Vehicle Technology
- Each Technology Bundle includes:
  - — Long-term vision document
  - — Reference model
  - — Roadmap



IEEE Synchrophasor Measurement Test Suite Specification (TSS)

- The TSS is a test specification required to design phasor measurement unit products (PMU)
- Provides a comprehensive, dependable plan that any manufacturer globally can use in the design stage to test their PMU products for eventual certification of IEEE C37.118.1™*
- Essential to many organizations working in smart grid technology.
- **Who needs the TSS?**
  - Utilities companies worldwide
  - PMU manufacturers
  - Traditional meter companies making the transition to Smart Grid technology
  - Small startups who are eager to capitalize on the market
  - Universities with a strong power engineering program & strong partnerships with industry



IEEE

* IEEE C37.188.1: "Standard for Synchrophasor Measurements for Power Systems"

Why are Synchrophasors so important?

- **Synchrophasors** are considered one of the most important measuring devices in the future of power systems.
- A mailbox-sized, monitoring device that can measure the instantaneous voltage, current & frequency at specific locations on the grid
- They give operators a near-real-time picture of what is happening on the system and allows them to make decisions to prevent power outages.
- By providing more accurate and timely data on system limits, synchrophasors make the grid more reliable and efficient, ultimately reducing planning and operations costs.

Learn More: www.ieee.org/go/synchrophasor-subscriptions

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Building Partnerships

- Goal for IEEE *Xplore* to become the technology destination of choice worldwide
- Need to enable users to find other high quality content to help fulfill their needs
- IET and IEEE: partners since 1988
  - Journals and conference proceedings are included in IEL subscriptions
  - IET represents over 200,000 articles in IEEE *Xplore*!
- IEEE *Xplore* now hosts select content from other leading society publishers:
  - IEEE-Wiley eBooks Library
  - IBM Journal of Research and Development
  - Tsinghua Science and Technology Journal
  - Journal of Systems Engineering and Electronics from the Beijing Institute of Aerospace Information
  - VDE Conference Proceedings
  - MIT Press
  - Morgan & Claypool

IET

IBM

TSINGHUA UNIVERSITY 1911

VDE

The MIT Press

IEEE

Bell Labs Technical Journal Now Available IEEE *Xplore*

The in-house scientific journal for scientists of Bell Labs/Alcatel-Lucent

- Delivered via IEEE *Xplore*
- More than 92 years of innovative research
- 26 new articles will be published each year
- Over 6,200 individual articles, backfile to 192
- Key research from leaders in the telecommunications, computer science, and engineering industries
- Peer-reviewed scientific journal for the global research and technical community
- A selected list of 40 seminal articles from the backfile now available for free on IEEE *Xplore*

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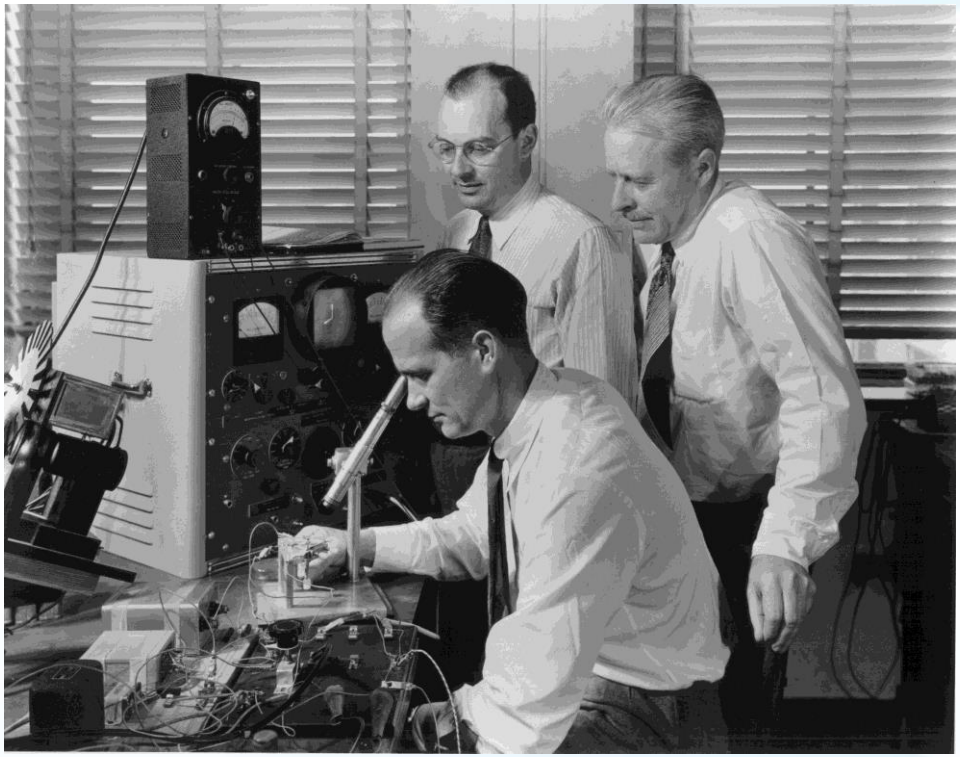
Historic content from BLTJ

Volume 28, 1949

- Invention of the first Transistor
- Fundamental building block of modern electronic devices
- Research won a Nobel Prize in 1947
  - William Shockley
  - John Bardeen
  - Walter Brattain



Historic content from BLTJ

Volume 42, 1963

- Telstar
- World's first active communications satellite
- Was able to transmit television signals and collect data on radiation in space

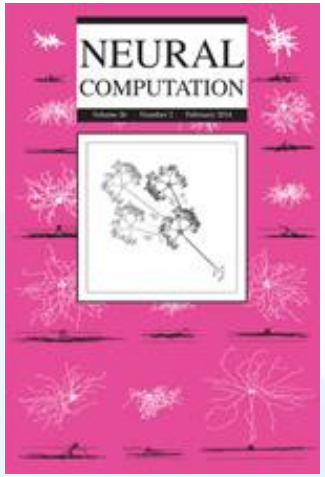
Other Seminal Papers from Bell Labs

- The Unix-Time Sharing System (1978)
  - The original paper describing the Operating System
- A mathematical theory of communication (1948)
  - Defined the field of information theory
- In-Band Single-Frequency Signaling (1954)
  - Enabled the famous “Blue Boxes”
- Number One Electronic Switching System (1964)
  - The first stored-program telephone switch, a technological marvel of its day
- The Cellular Concept (1978)
  - Plan to create mobile telephone service on a large scale

MIT Press Journals Library
Computer & Engineering Collection

- IEEE has partnered with the MIT Press to bring a subset of their high quality journals to the IEEE Xplore digital library.
- 8 specially selected titles from the MIT Press in leading Science and Technology areas such as:
  - Artificial Intelligence
  - Evolutionary Computation
  - Cognitive Neuroscience
  - Neural Computation
  - Linguistics
  - Teleoperators
  - Virtual Environments
- Unlimited full-text access to more than 10,000 articles
- Backfile to 1989
- Complete package available exclusively on IEEE Xplore

  Available as a subscription add-on



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Three Leading eBook Collections now in IEEE *Xplore*

- **IEEE-Wiley eBooks Library**
  - More than 700 eBook titles from the Wiley-IEEE Press
  - Backfile to 1974
- **MIT Press eBooks Library-Computing & Engineering Collection**
  - Nearly 600 eBook titles from the MIT Press with more than 70% of titles in computing related fields
  - Backfile to 1943
- **Morgan & Claypool Synthesis eBooks Library**
  - Access nearly 700 peer-reviewed titles focusing on computer science
  - Backfile to 2006

Available as subscription add-ons
Perpetual access options available

New! – SMPTE content in IEEE Xplore

IEEE has partnered with SMPTE, the Society of Motion Picture and Television Engineers®, to be the exclusive host for the complete SMPTE Digital Library for institutional customers.

- SMPTE Motion Picture and Television Standards and Practices— more than 800 Standards
- Proceedings from the Annual SMPTE Technical Conference & Exhibition – more than 2,000 papers
- Peer-reviewed SMPTE Motion Imaging Journal – more than 20,000 articles

Available as subscription add-ons
Perpetual access options available

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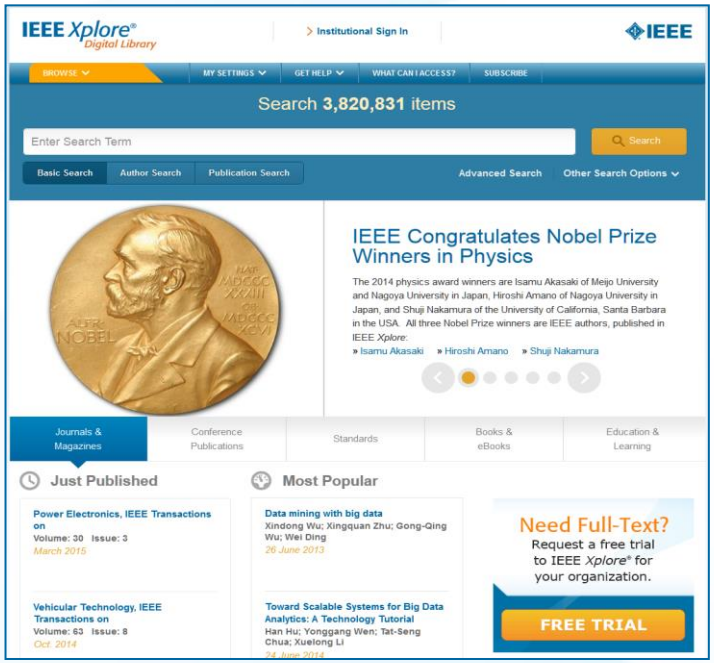
Recent enhancements to IEEE *Xplore*

IEEE *Xplore* now provides:

- Multiple authentication options for onsite, remote, and mobile users
- Enhanced interactive HTML format with ability to view and copy equations and mathematical formulas multiple formats
- New collaboration tools
- And much more….

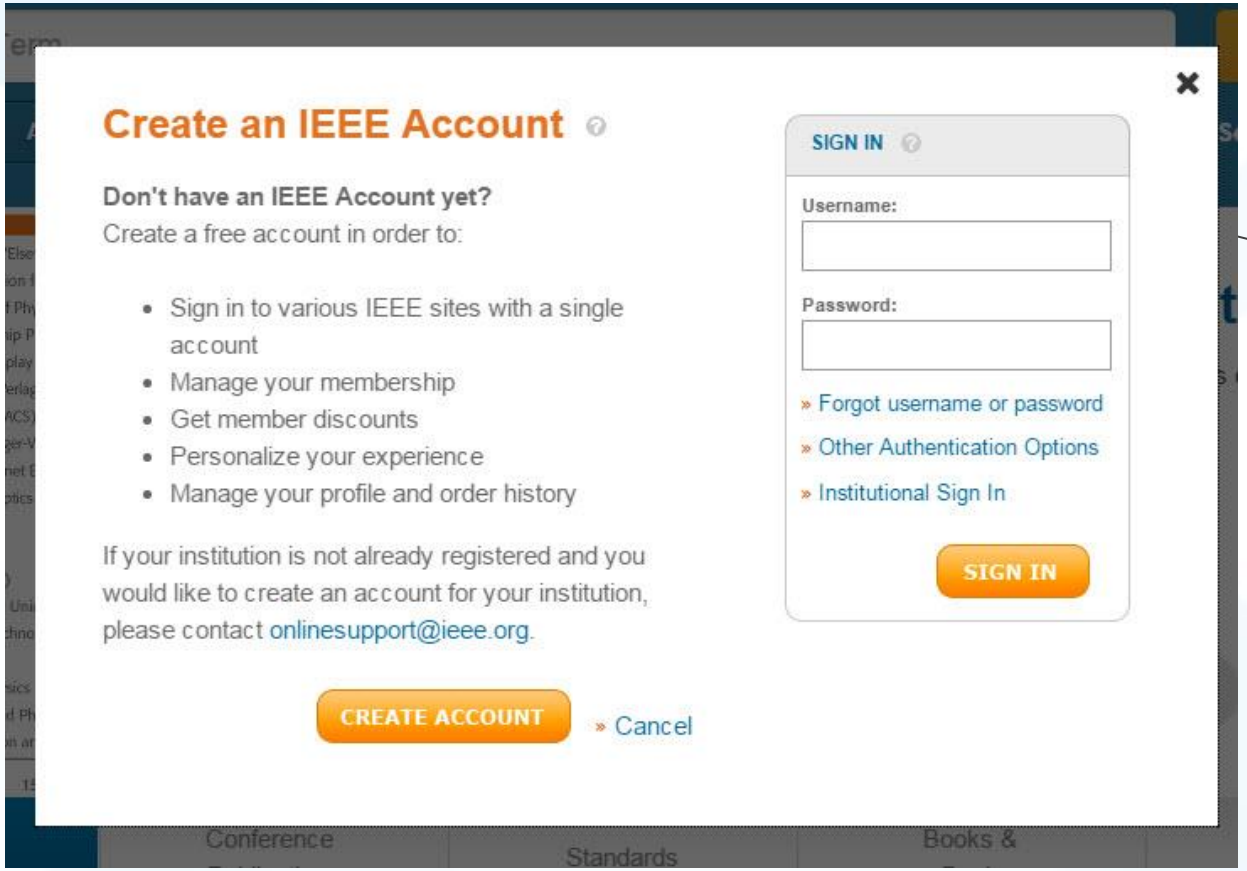


IEEE

Create a free personal account

Why use a IEEE Xplore Personal Account?

- **Search preferences**
- **Set-up search and content alerts**
- **Use search history**
- **Enable remote access feature & more…**



3-click process – just fill out your First Name, Last Name, email address, password and two security questions.

Personal account benefits

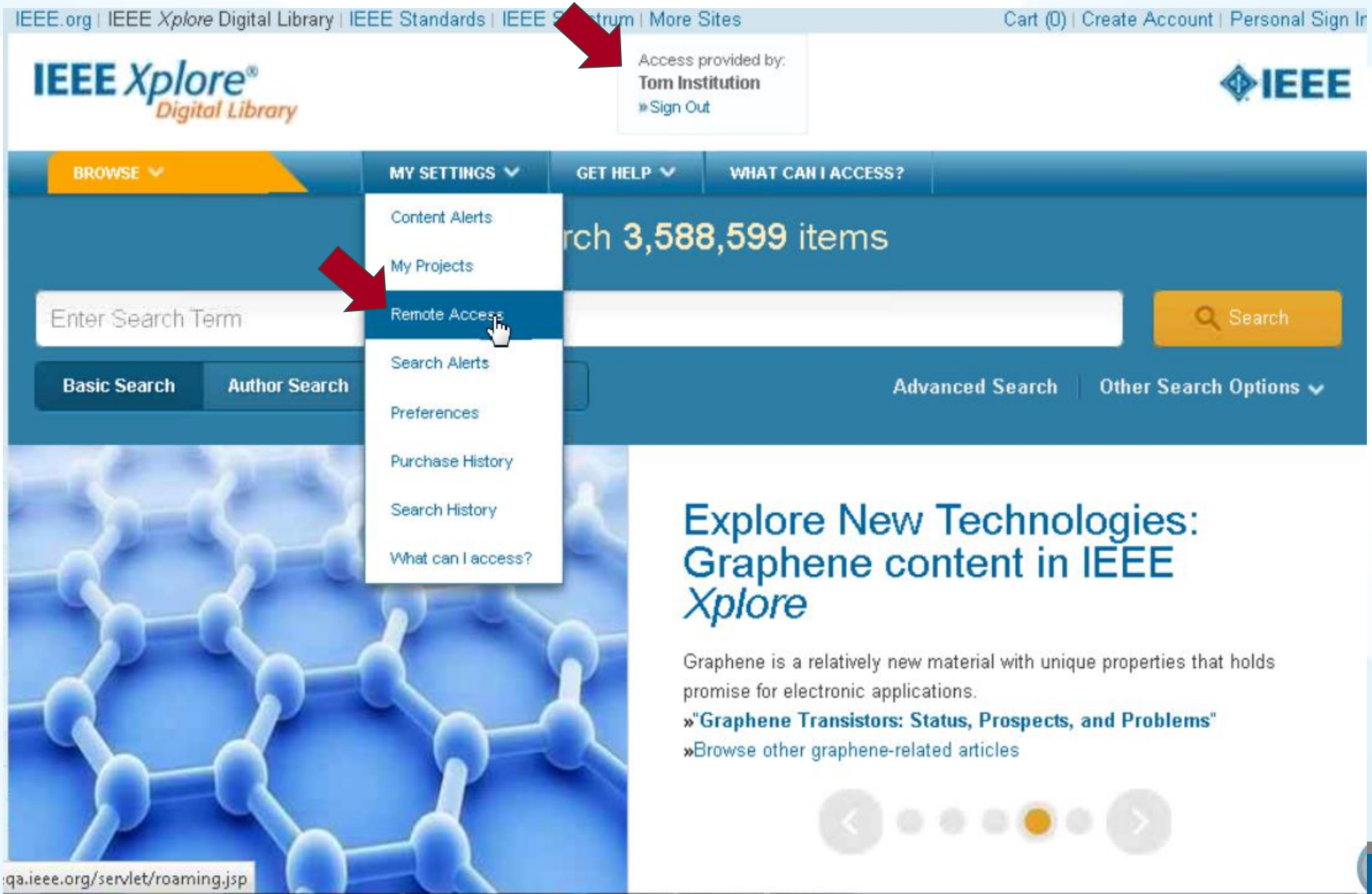
- ***Search Preferences***: Designate what you want to search and how you want your search results displayed in IEEE *Xplore* by setting search preferences.
- ***Search History***: Search history allows you to record your 50 most recent searches for later viewing and create more complex searches by combining searches. Turn on the search history recording feature in your Preferences.
- ***Saved Search Alerts***: Stay up-to-date with the latest research by saving your search. IEEE will notify you when new articles of interest are available.
- ***Table of Contents Alerts***: Sign up to receive an email when a new journal or magazine in your area of interest has been posted online with a link to the Table of Contents.
- ***Collabratec***: Create personal Research Collections to keep documents organized by project or topic within IEEE *Xplore*. Personalize with project descriptions, and add notes and tags to individual articles as you save them. ***(formerly My Projects)***

Remote Access

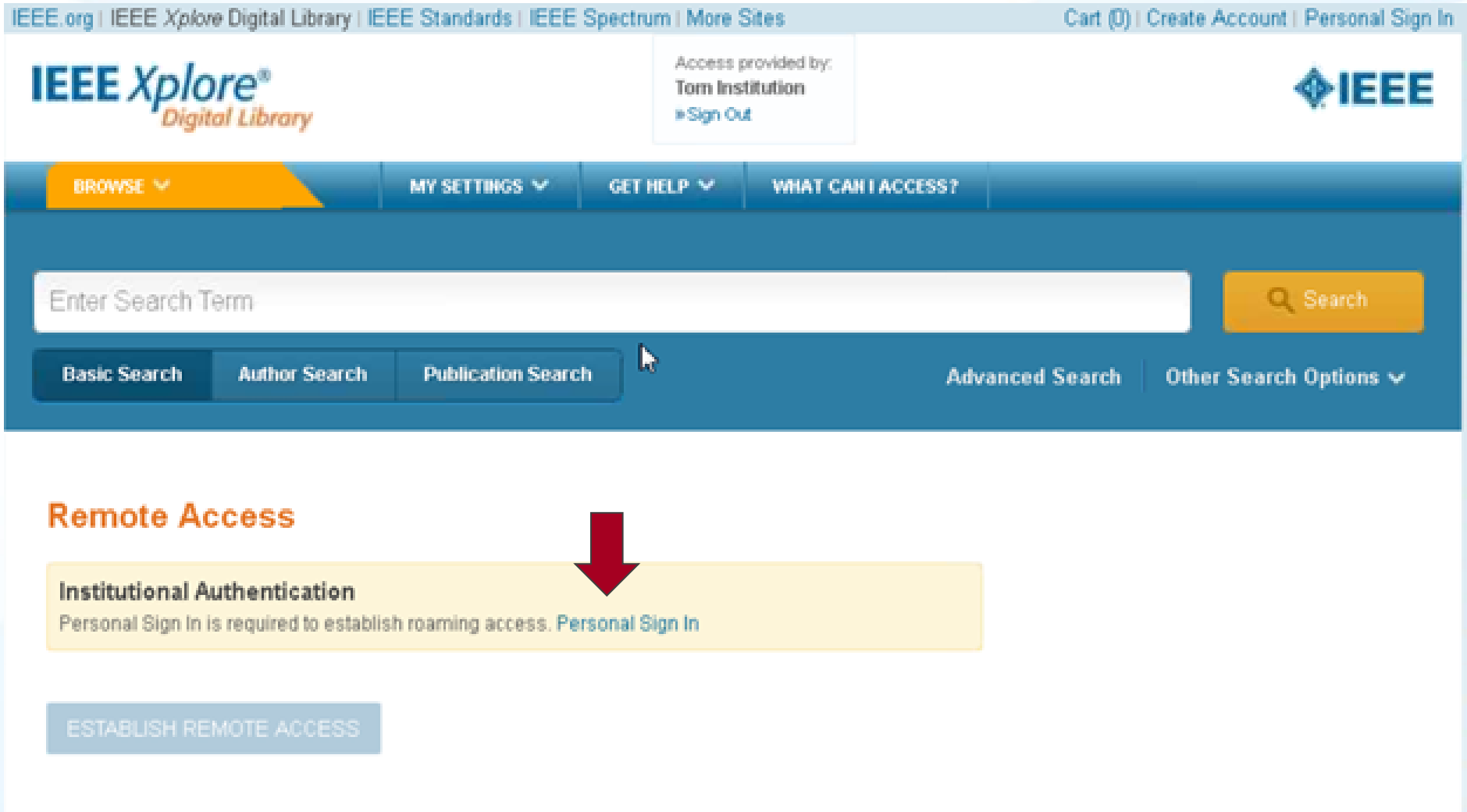
- Allows for remote mobile access to IEEE *Xplore* content when users are off-campus
- Can be set-up for multiple devices – laptop, tablet, phone
- Available for 90 days
- To initiate:
  - Login to IEEE *Xplore* from within your institution's IP range
  - Sign In with a personal IEEE Account
  - Select My Settings > Remote Access

Libraries can have this feature enabled by contacting Online Support (onlinesupport@ieee.org)

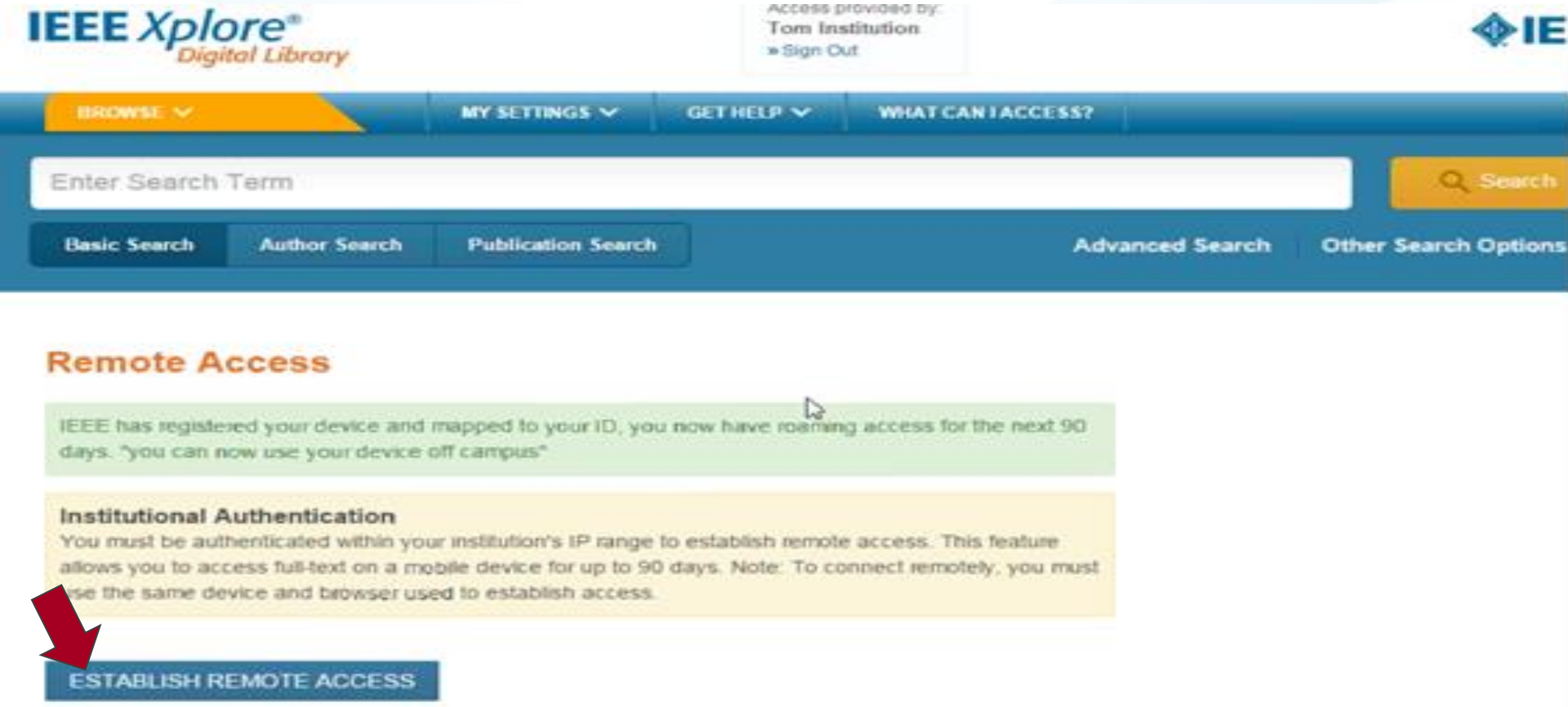
Setting Up Remote Access



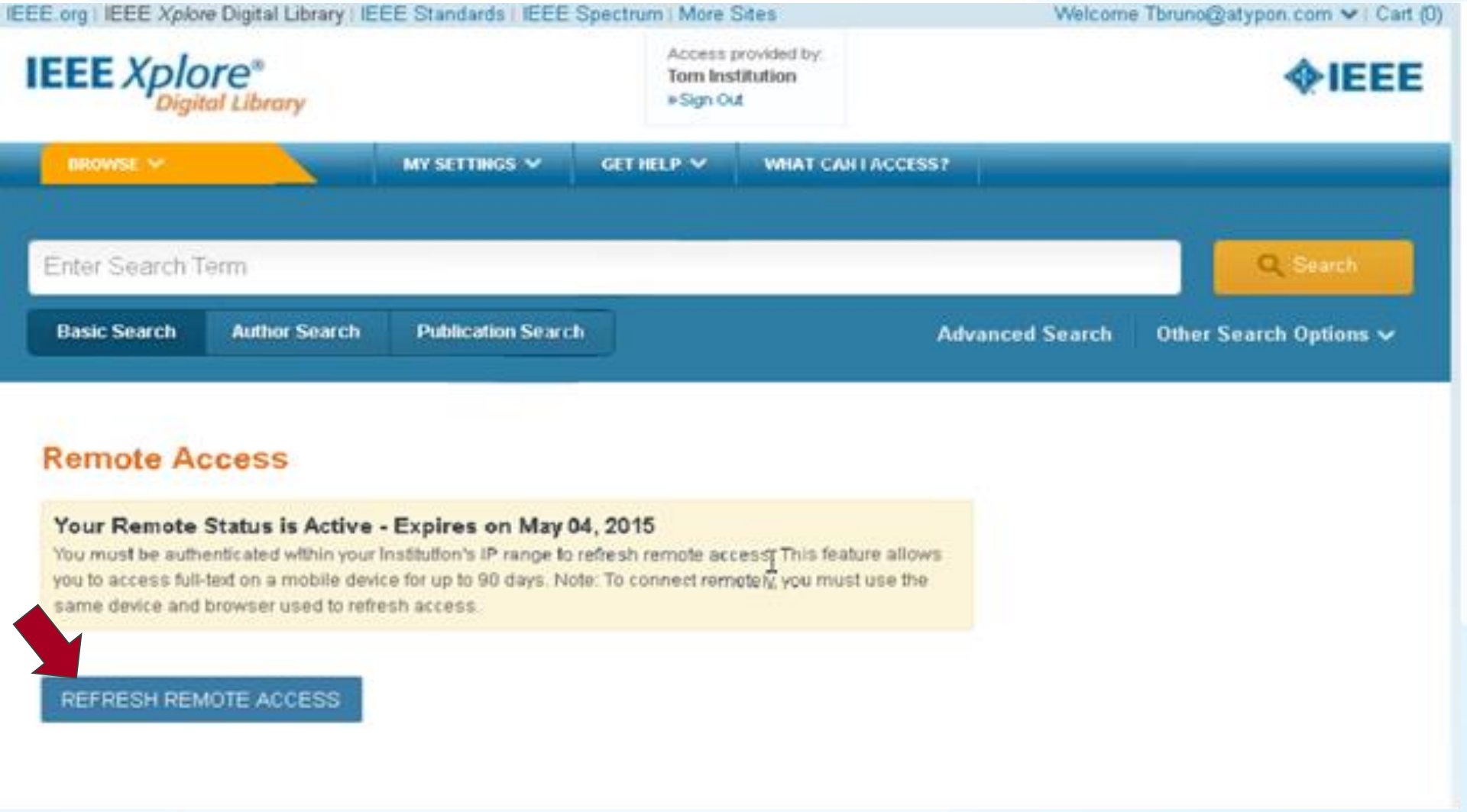
Sign in with personal IEEE account



Select Establish Remote Access to pair mobile device



Refresh remote access every 90 days

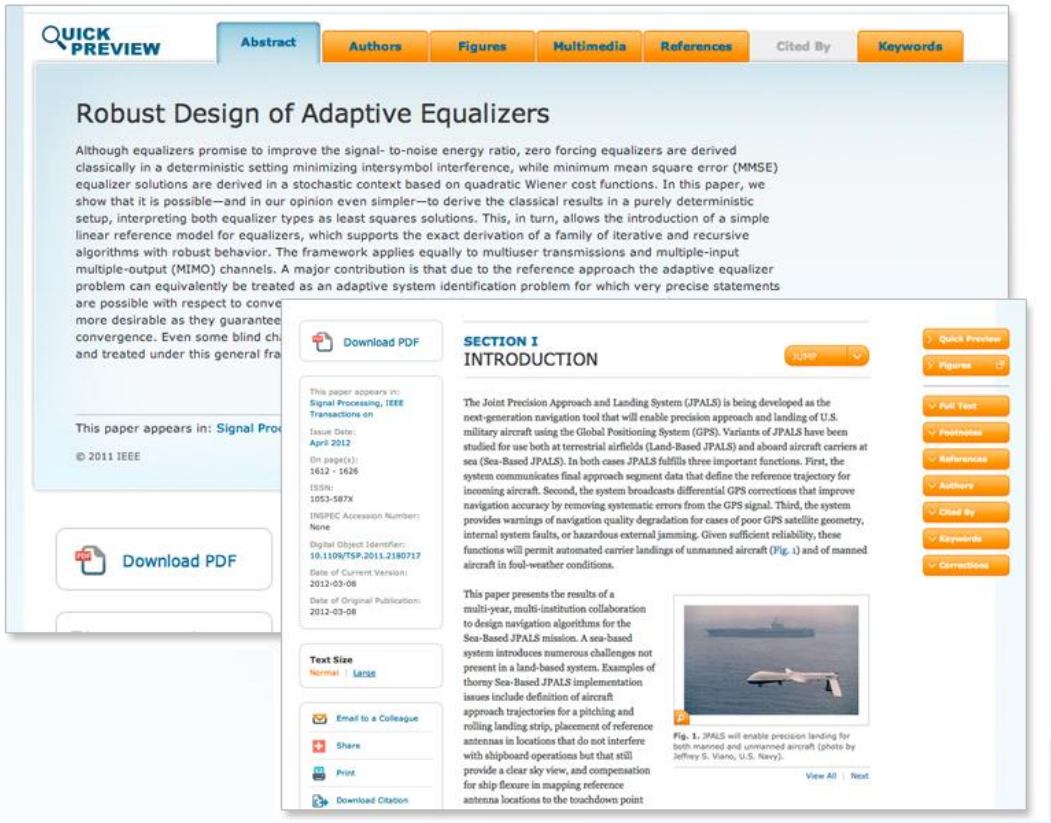


Remote Access

- This feature will be OFF by default. Libraries can have this feature enabled by contacting Online Support (onlinesupport@ieee.org)
- Institution must have WiFi available to their users and have added the WiFi IP address to their IEEE account authentication
- There is no limit to the number of devices a user can pair, but each individual device and browser on the device will need to be paired uniquely
- User must create/use their IEEE personal account to pair device as well as use the subscription on the paired device

Dynamic new layout with full-text HTML articles

- ☑ Scan and interpret articles in under 60 seconds using "Quick Preview”
- ☑ Navigate between sections of long articles with intuitive floating navigation
- ☑ Effortlessly explore text, figures, equations, and multimedia files
- ☑ Quickly view and copy mathematical equations, expressions, and formulas
- ☑ Enhance your research with recommendations for related articles



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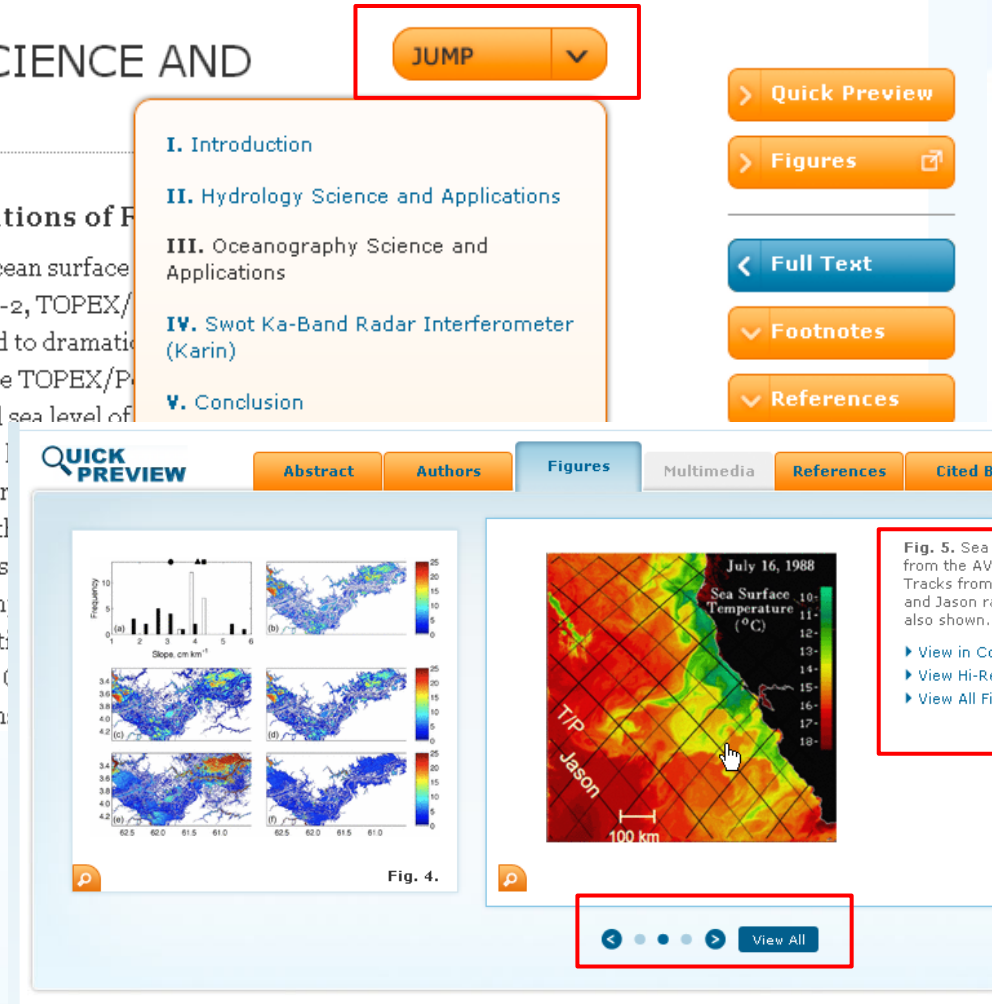
Intuitive navigation and interaction with full-text HTML



3.1 Formulation of Feature Combination

As discussed in Section 2, we treat the set of all possible appearances of the image patch surrounding a keypoint as a class. Therefore, given the patch surrounding a keypoint detected in an image, our task is to assign it to the most likely class. Let c_i , $i = 1, \ldots, H$, be the set of classes and let f_j , $j = 1, \ldots, N$, be the set of binary features that will be calculated over the patch that we are trying to classify. Formally, we are looking for

$$\hat{c}_i = \underset{c_i}{\operatorname{argmax}} \; P(C = c_i \mid f_1, f_2, \ldots, f_N),$$

▸ View Source

where C is a random variable that represents the class. Bayes' formula yields

$$\begin{aligned} & P(C = c_i \mid f_1, f_2, \ldots, f_N) \\ & = \frac{P(f_1, f_2, \ldots, f_N \mid C = c_i) P(C = c_i)}{P(f_1, f_2, \ldots, f_N)}. \end{aligned}$$

▸ View Source

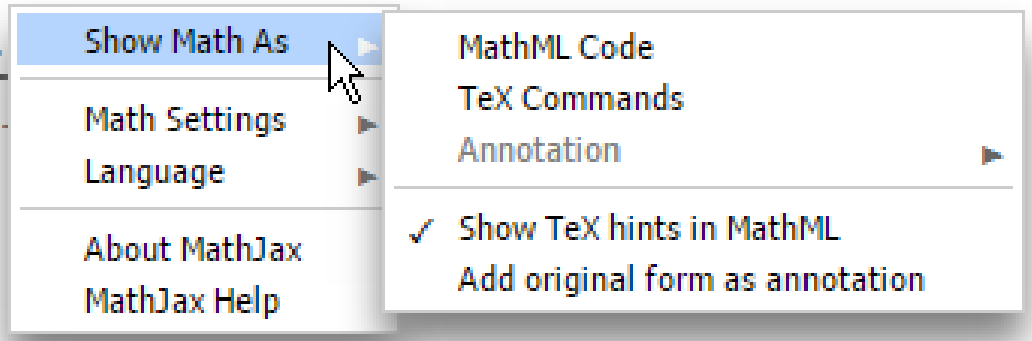
Assuming a uniform prior $P(C)$, since the denominator is simply a scaling factor that is independent from the class, our problem reduces to finding

$$\hat{c}_i = \underset{c_i}{\operatorname{argmax}} \, P(f_1, f_2, \ldots, f_N \mid C = c_i). \qquad (1)$$

where C is a random variable that represents the class. Bayes' formula yields

$$P(C = c_i \mid f_1, f_2, \ldots, f_N)$$

$$= \frac{P(f_1, f_2, .$$



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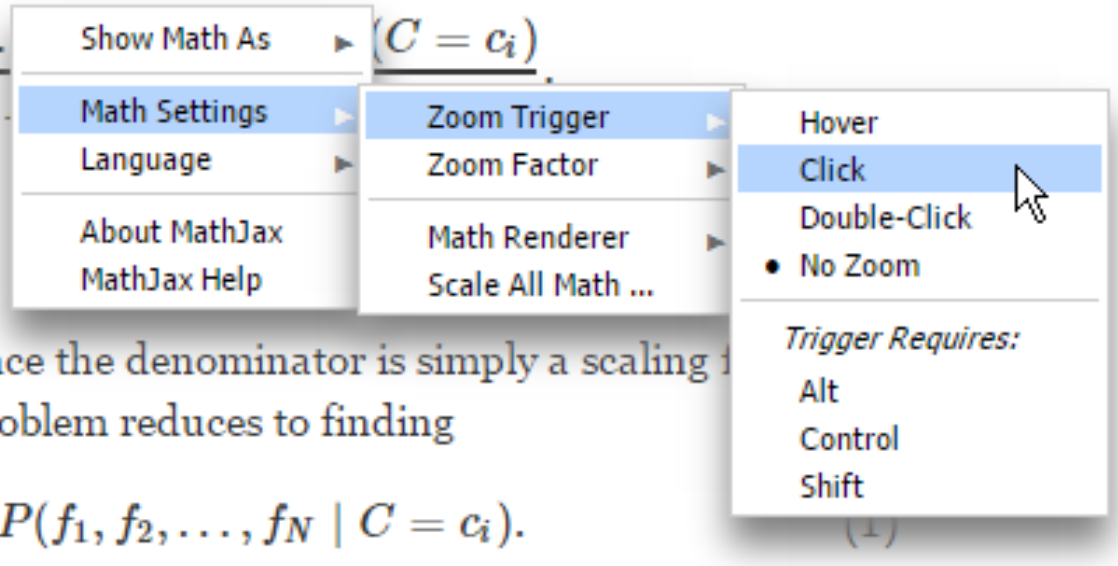
Assuming a uniform prior $P(C)$, since the denominator is simply a scaling factor that is independent from the class, our problem reduces to finding

where C is a random variable that represents the class. Bayes' formula yields

$$P(C = c_i \mid f_1, f_2, \ldots, f_N)$$
$$= \frac{P(f_1, f_2, .}{} (C = c_i)$$



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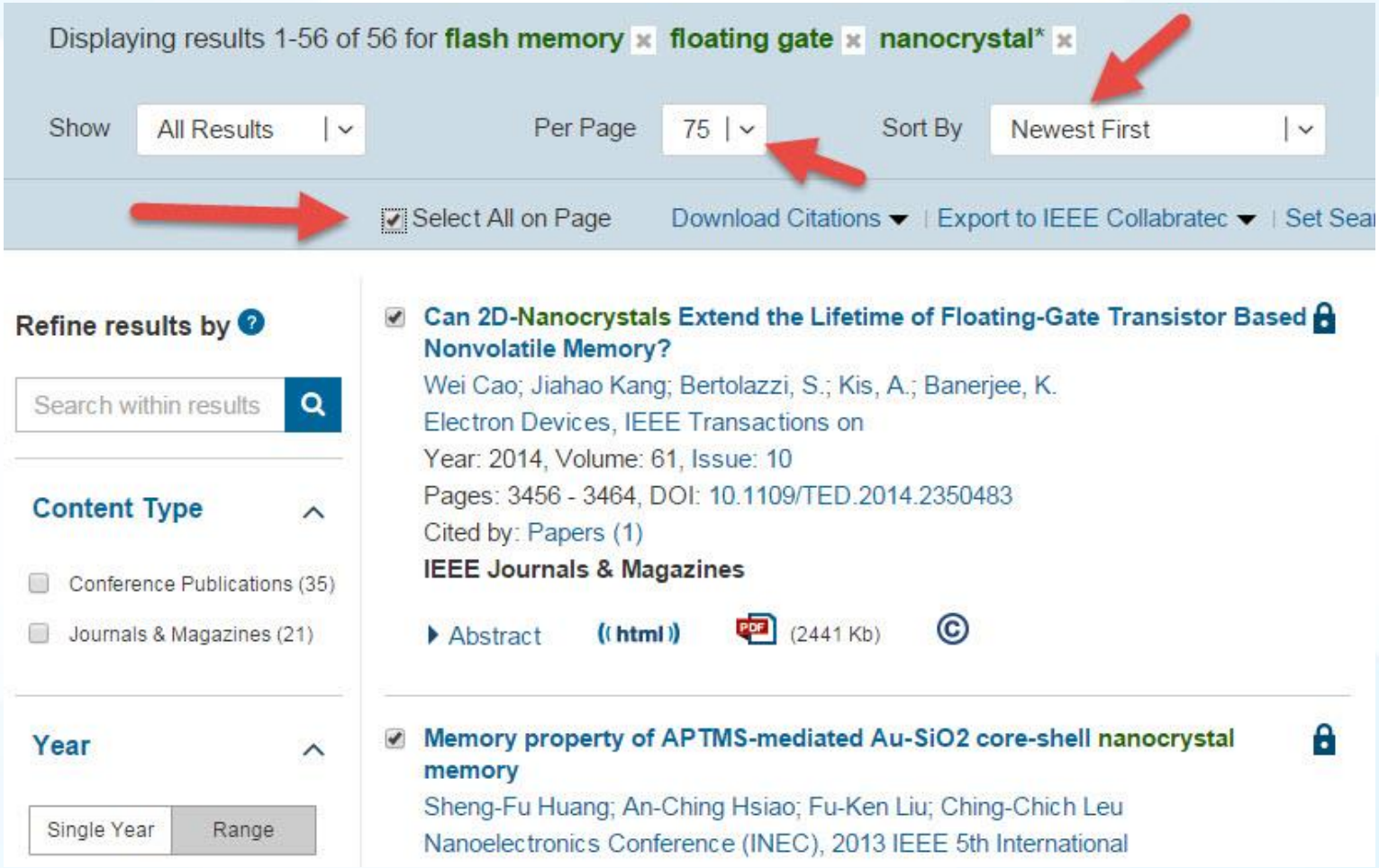
Assuming a uniform prior $P(C)$, since the denominator is simply a scaling f
is independent from the class, our problem reduces to finding

$$\hat{c}_i = \underset{c_i}{\operatorname{argmax}}\, P(f_1, f_2, \ldots, f_N \mid C = c_i).$$

Download citations from results page



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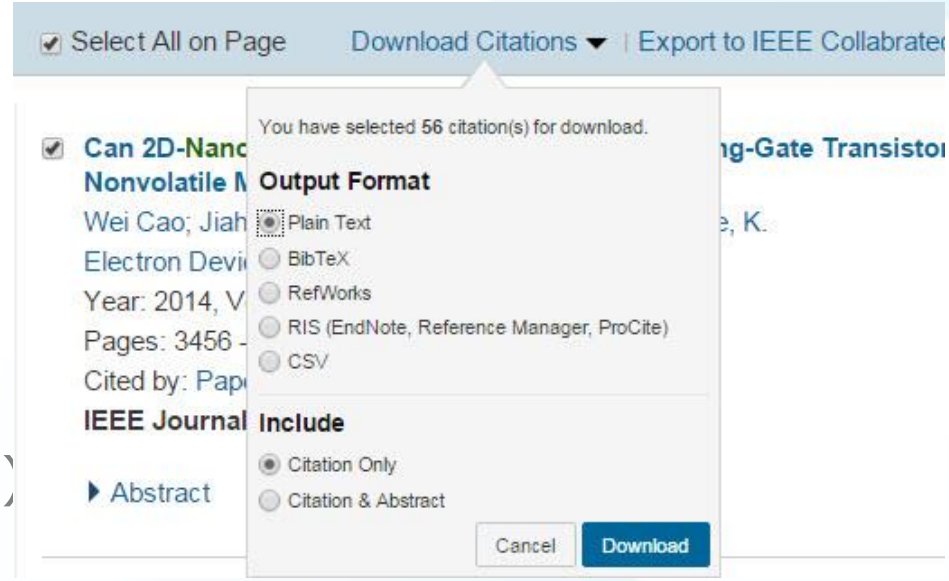

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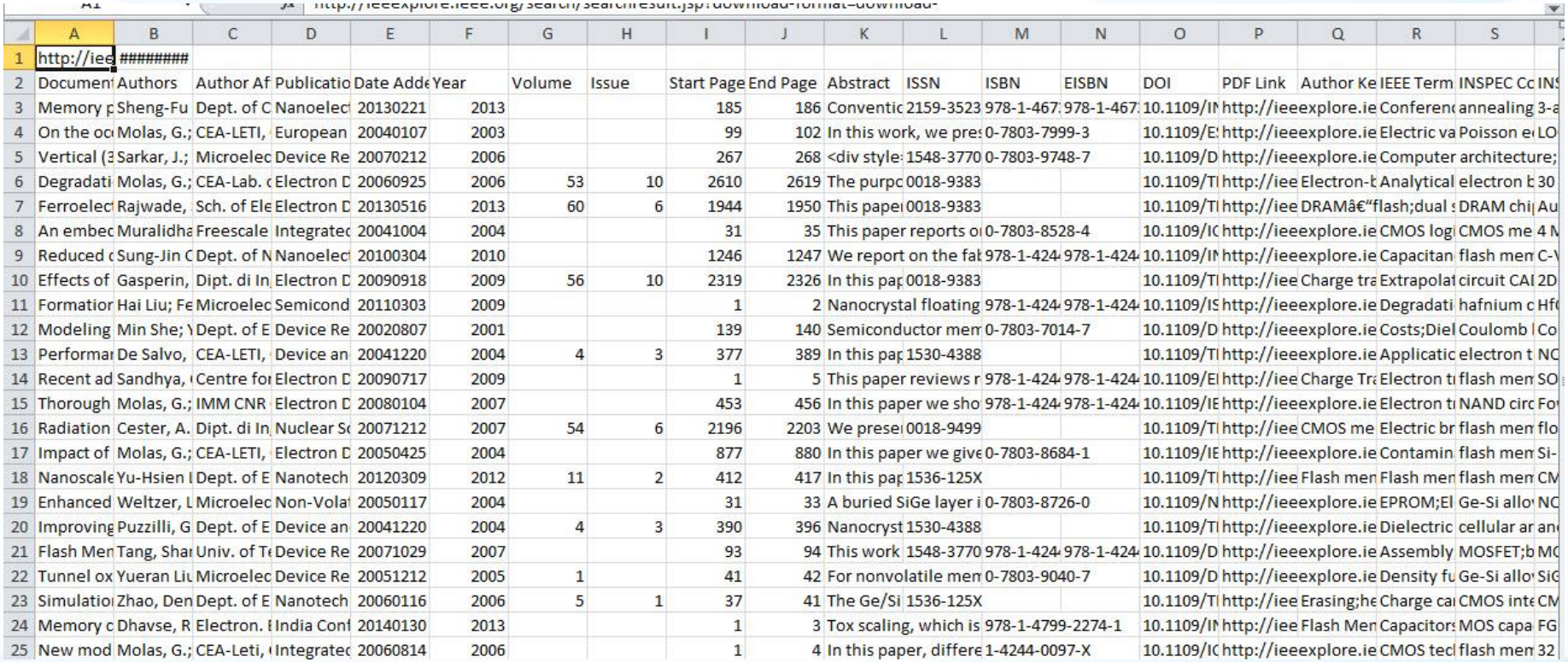
Up to 2000 records – check boxes not necessary



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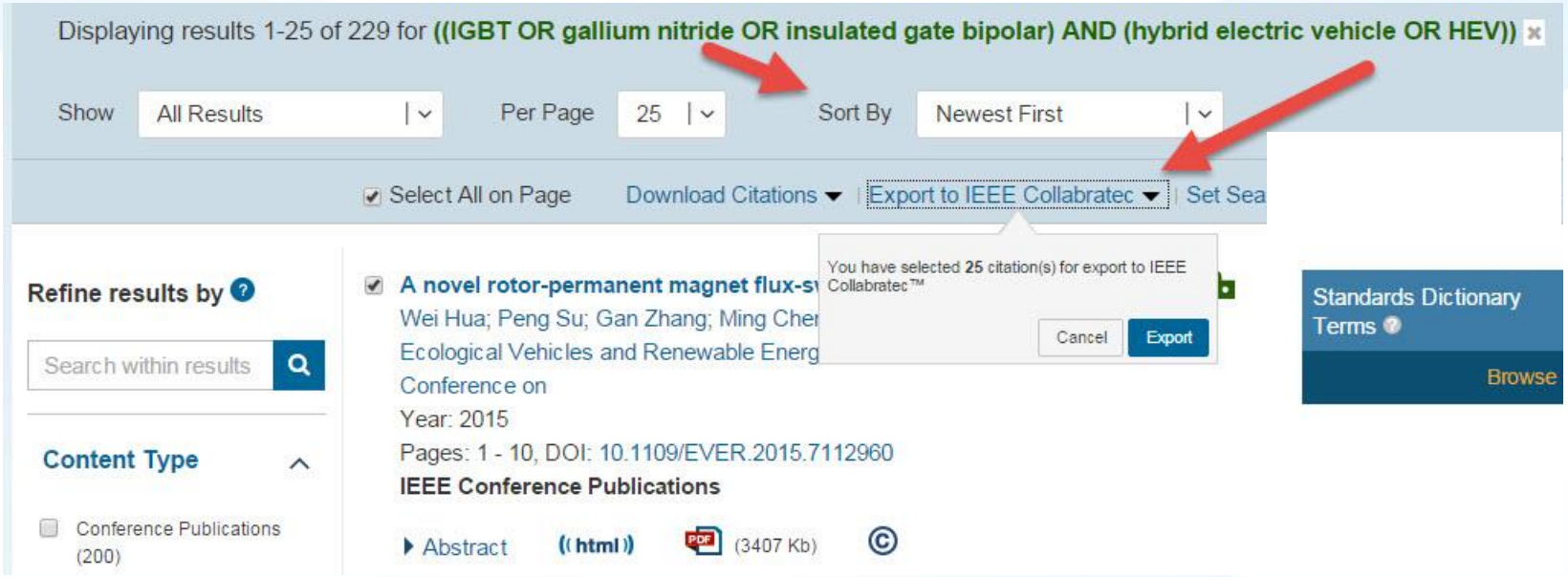

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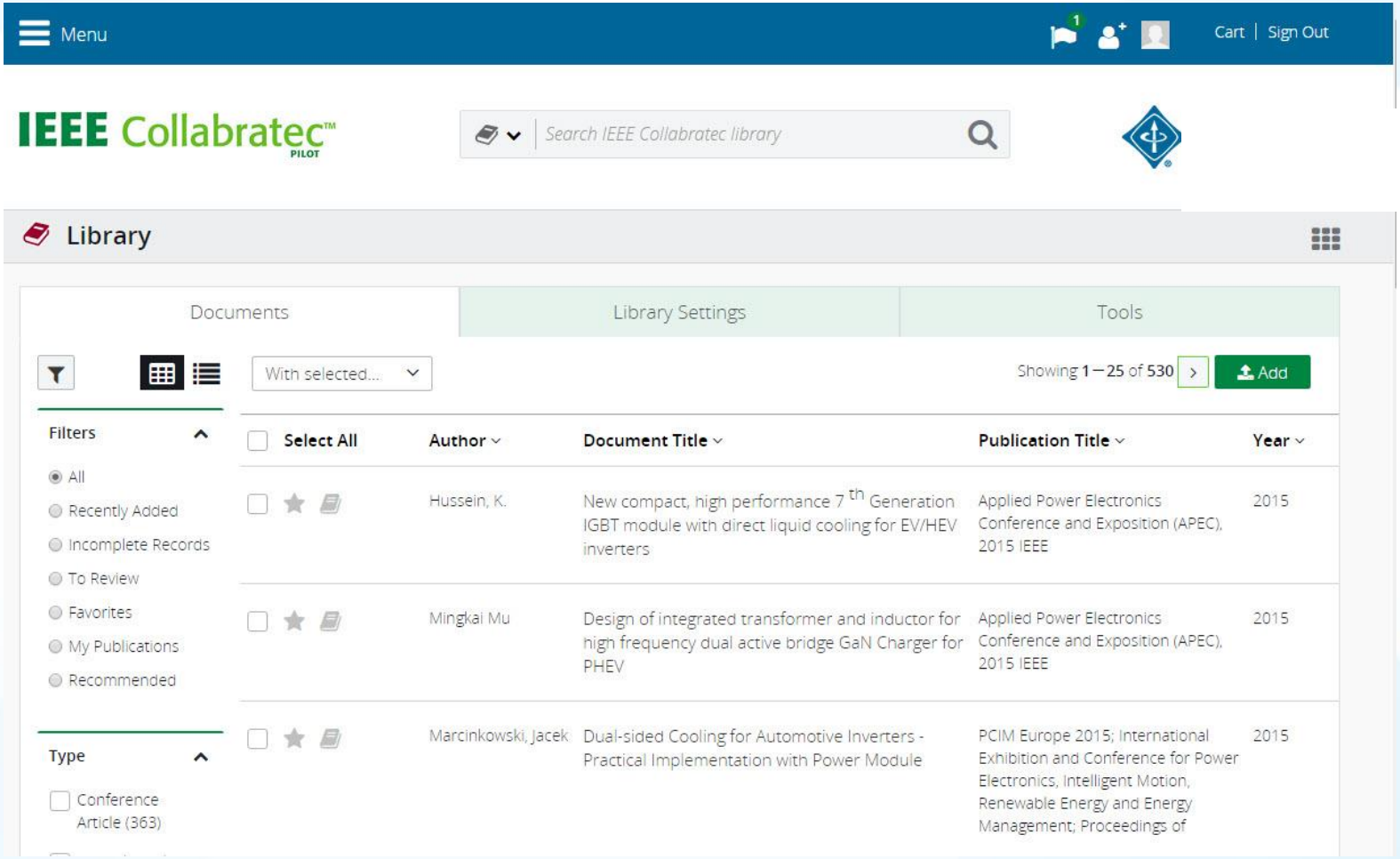

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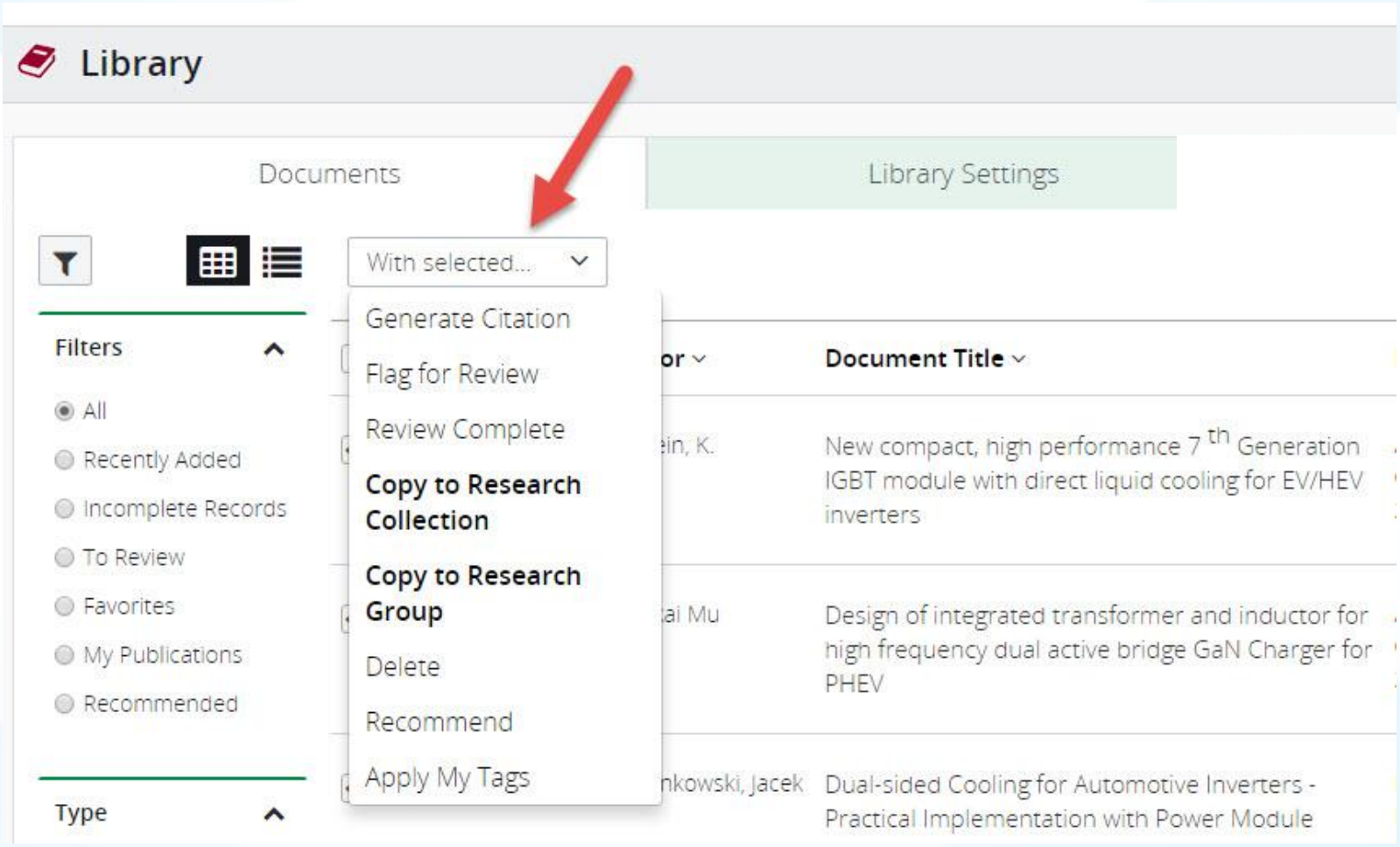

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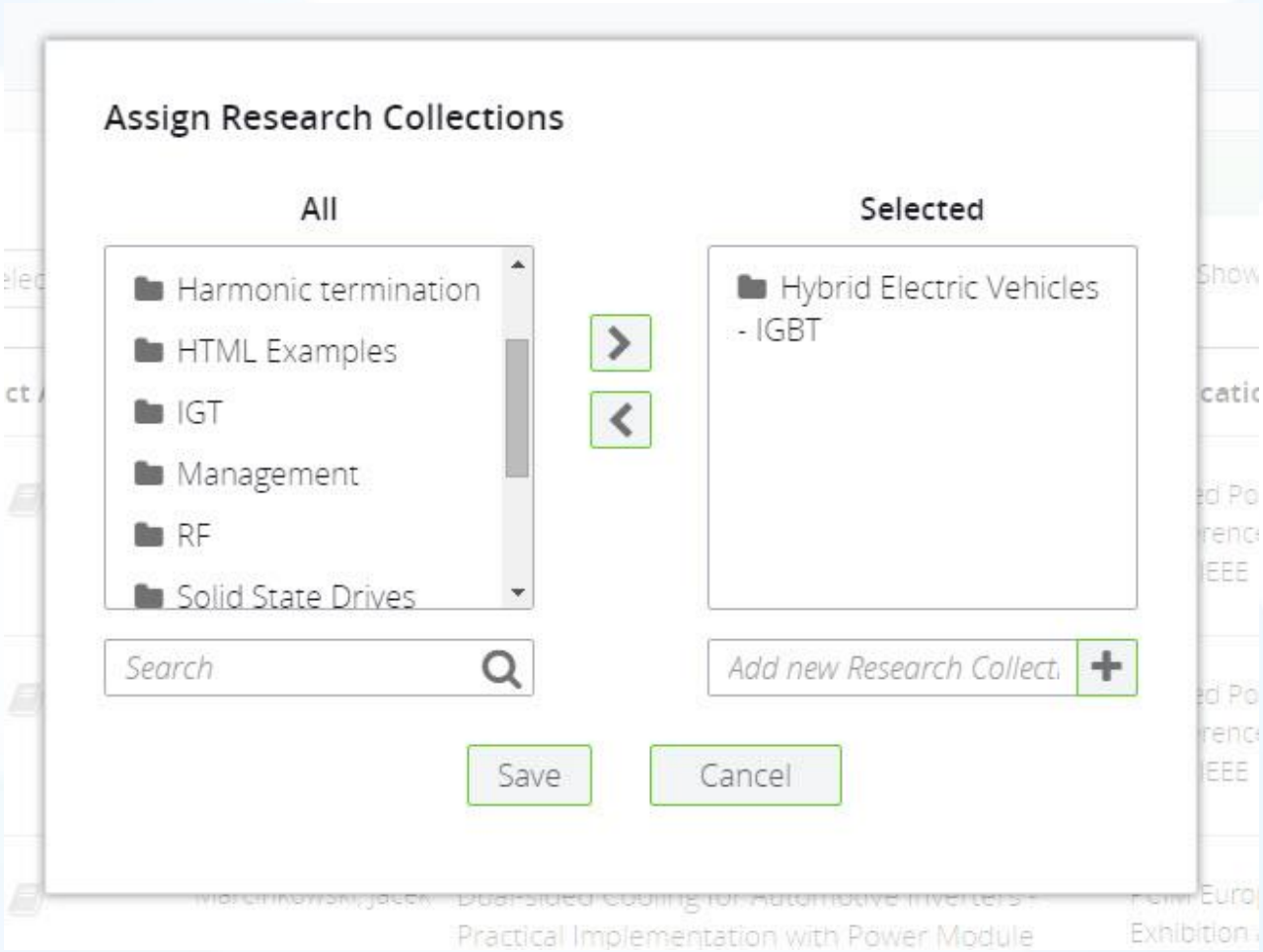

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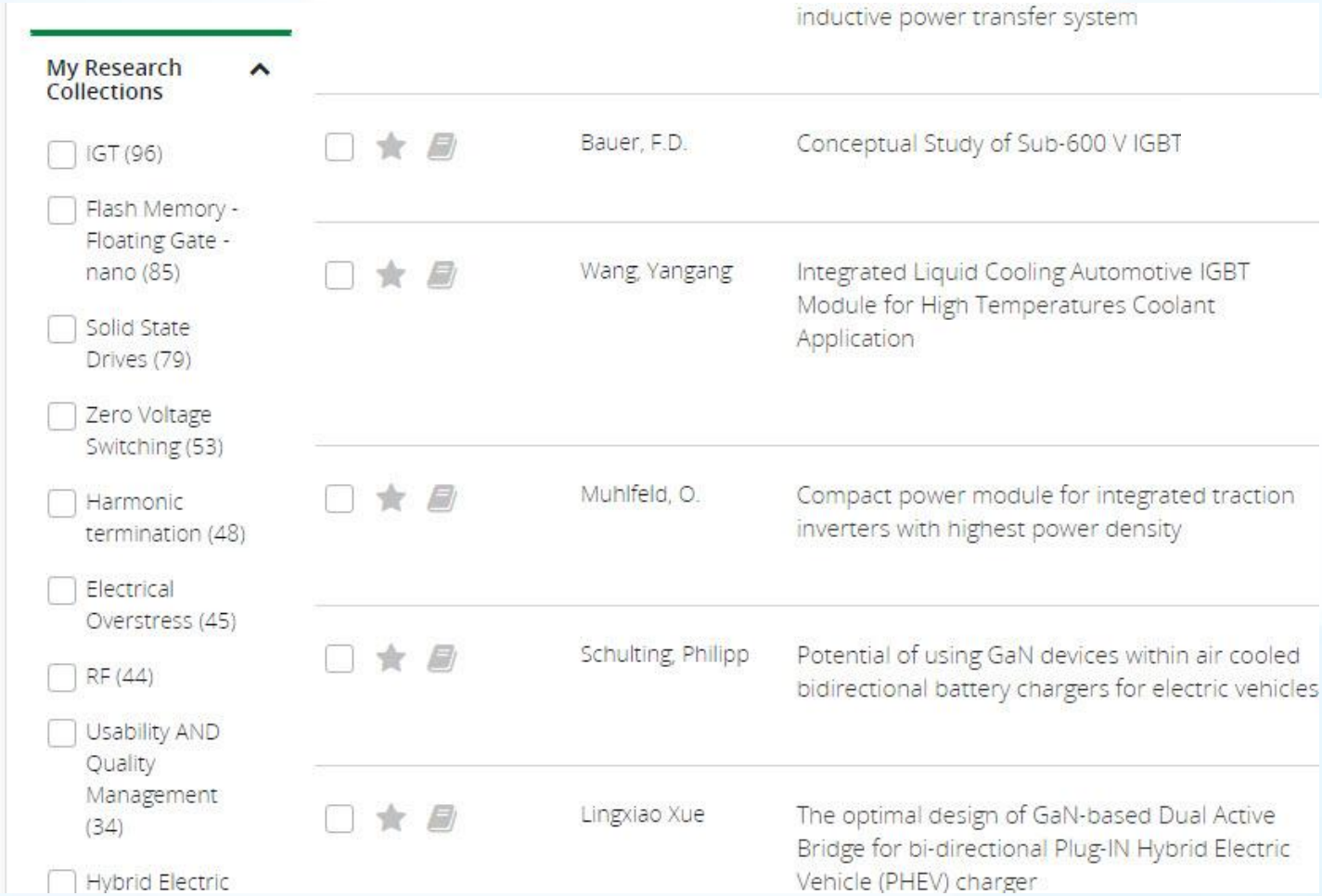

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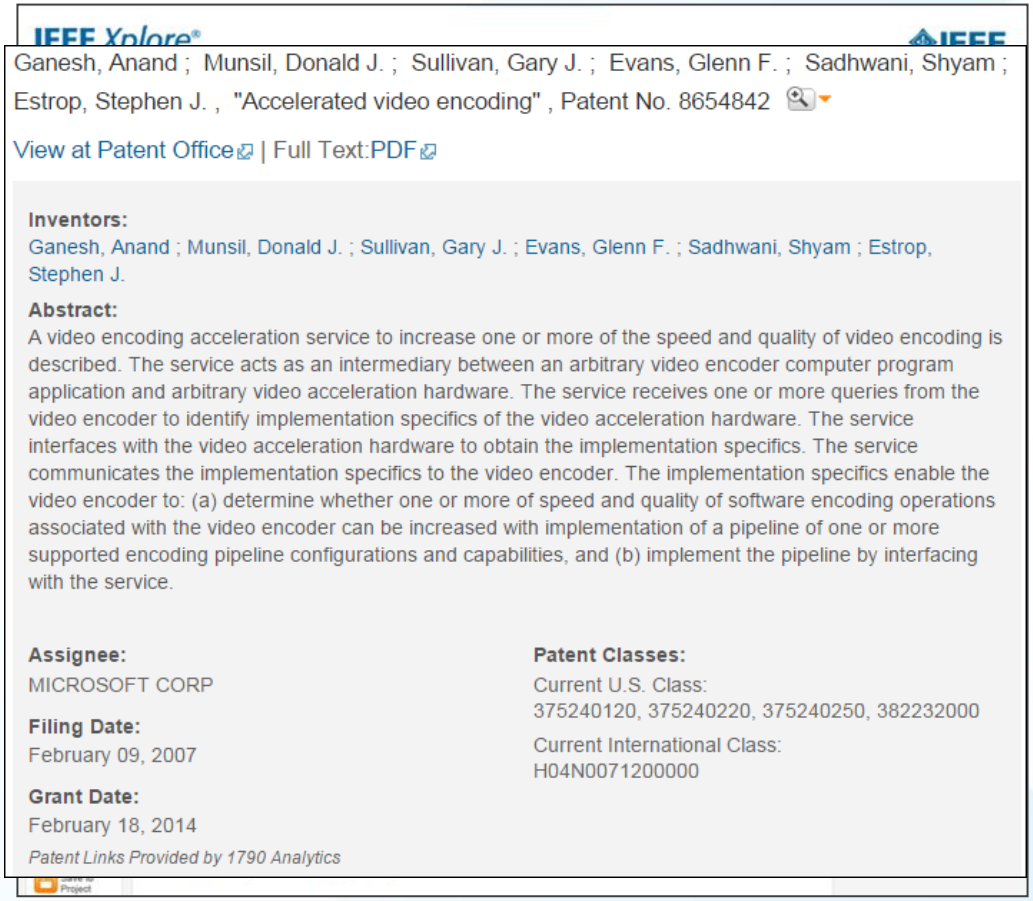

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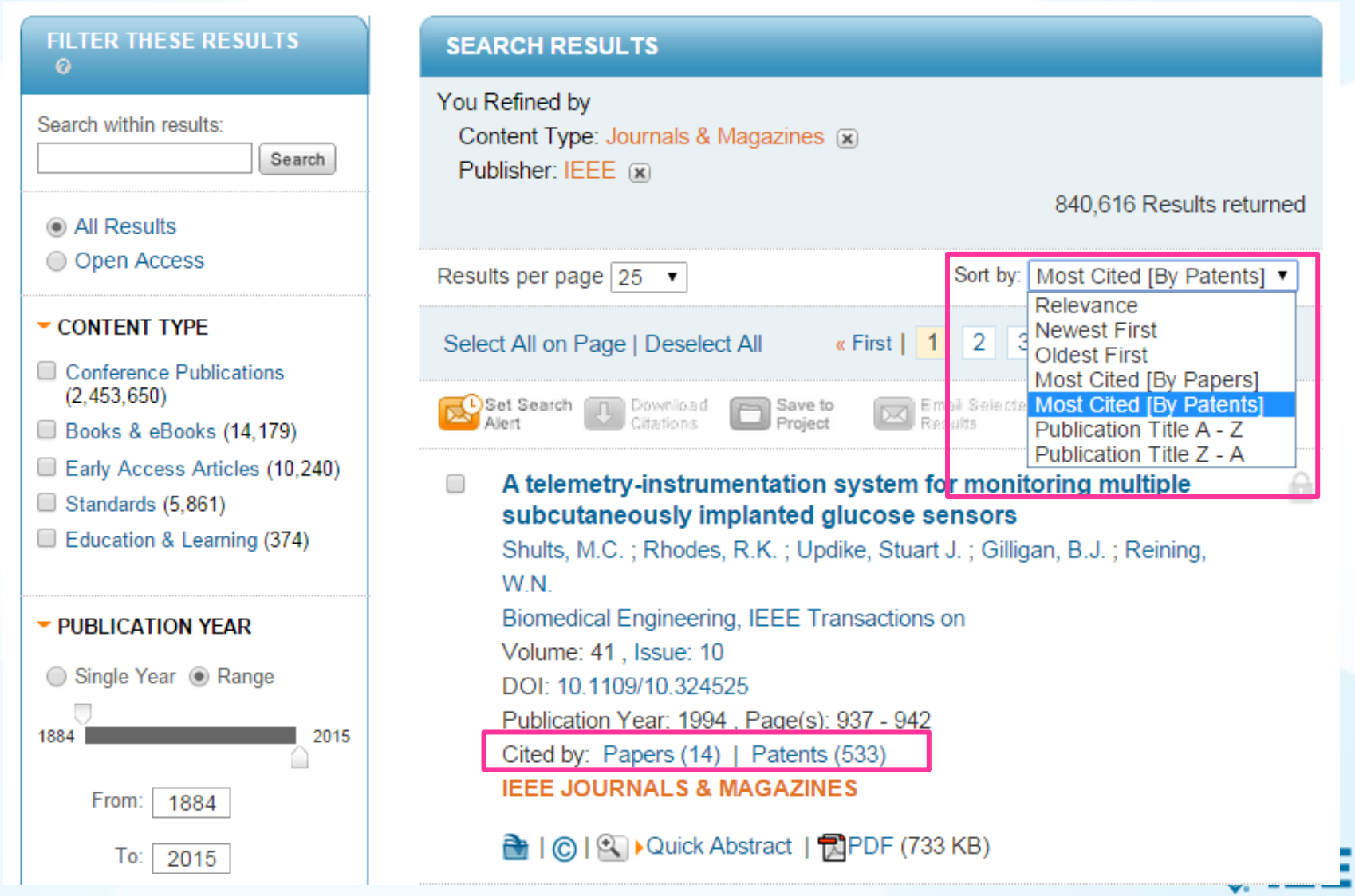

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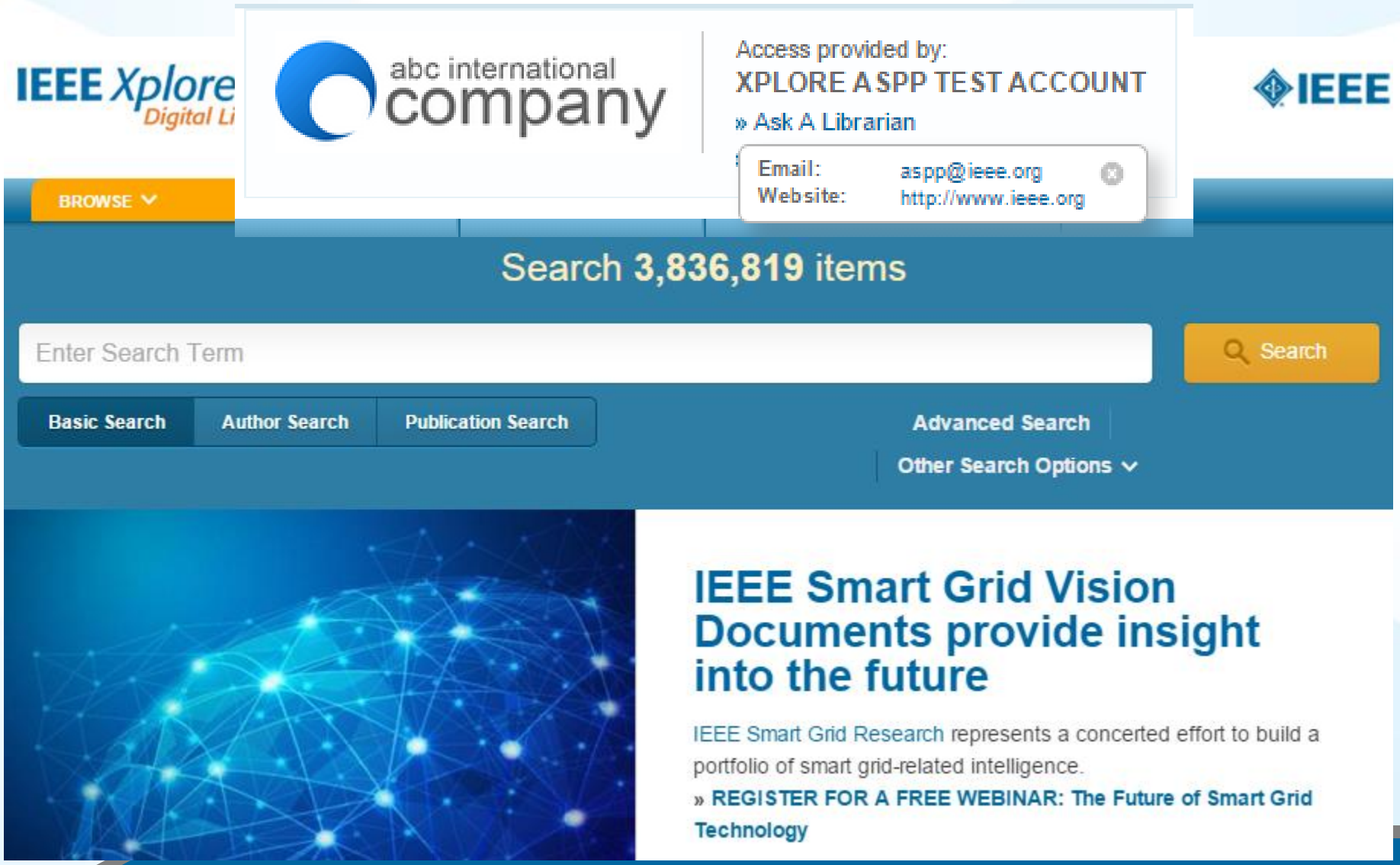

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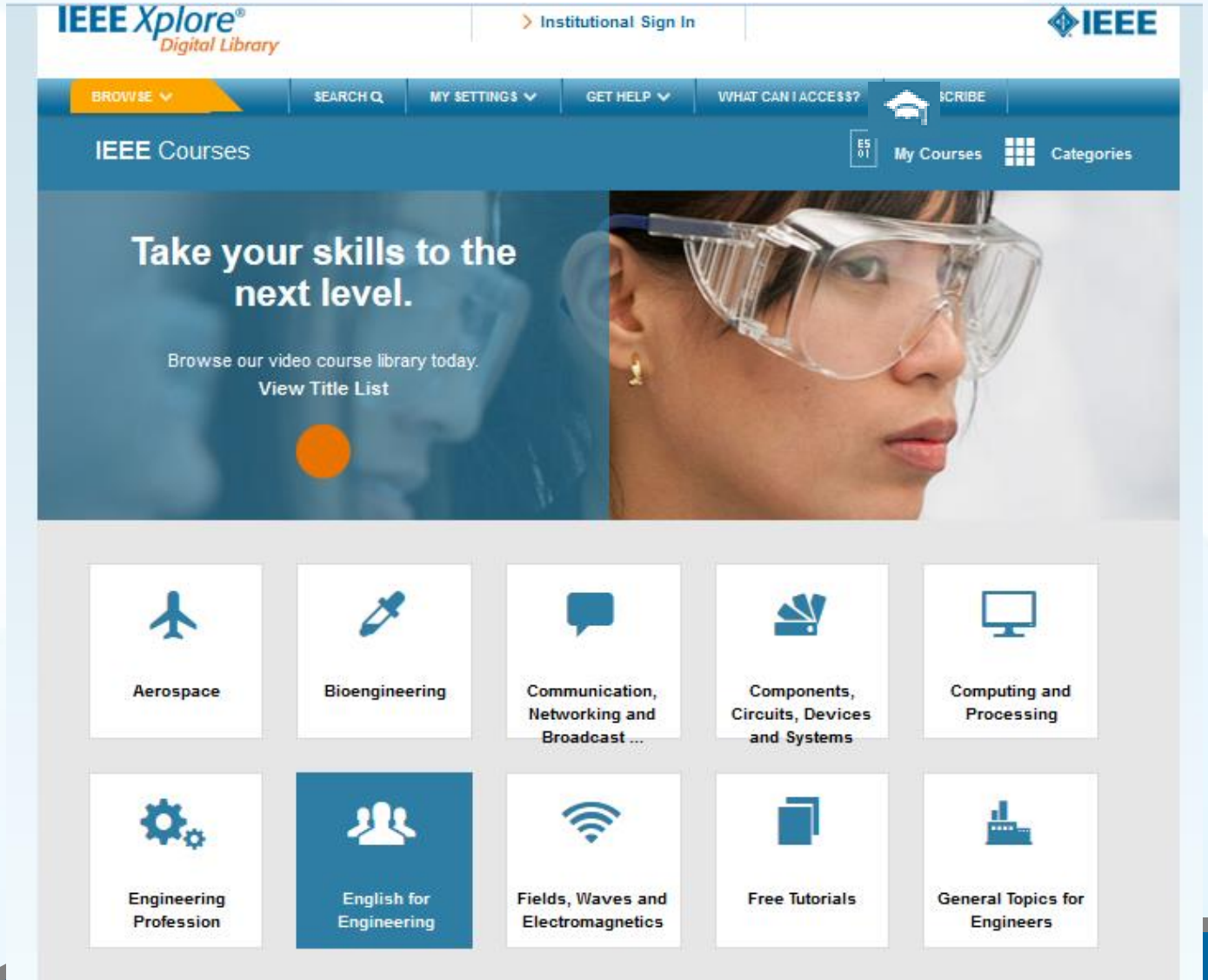

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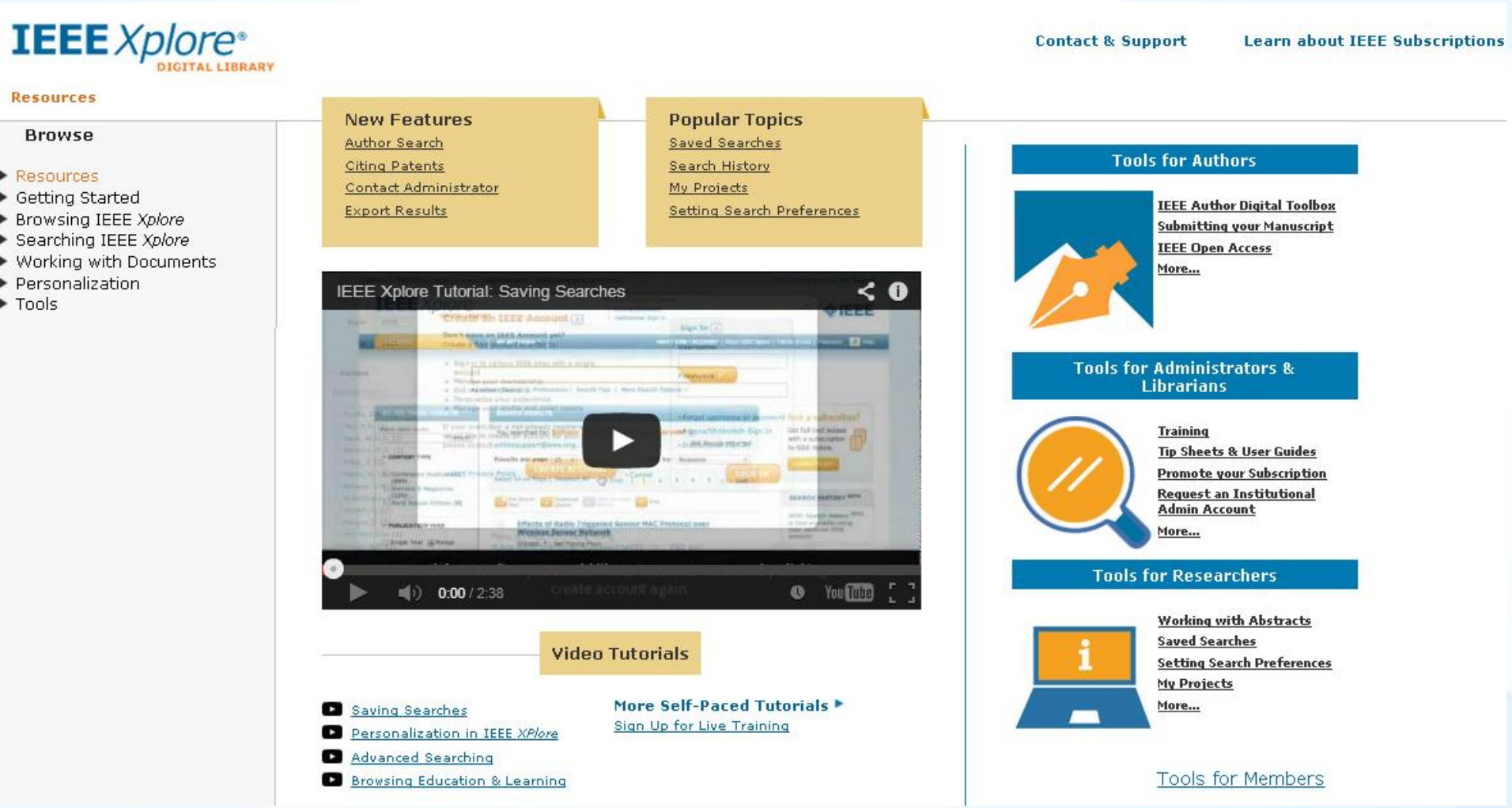

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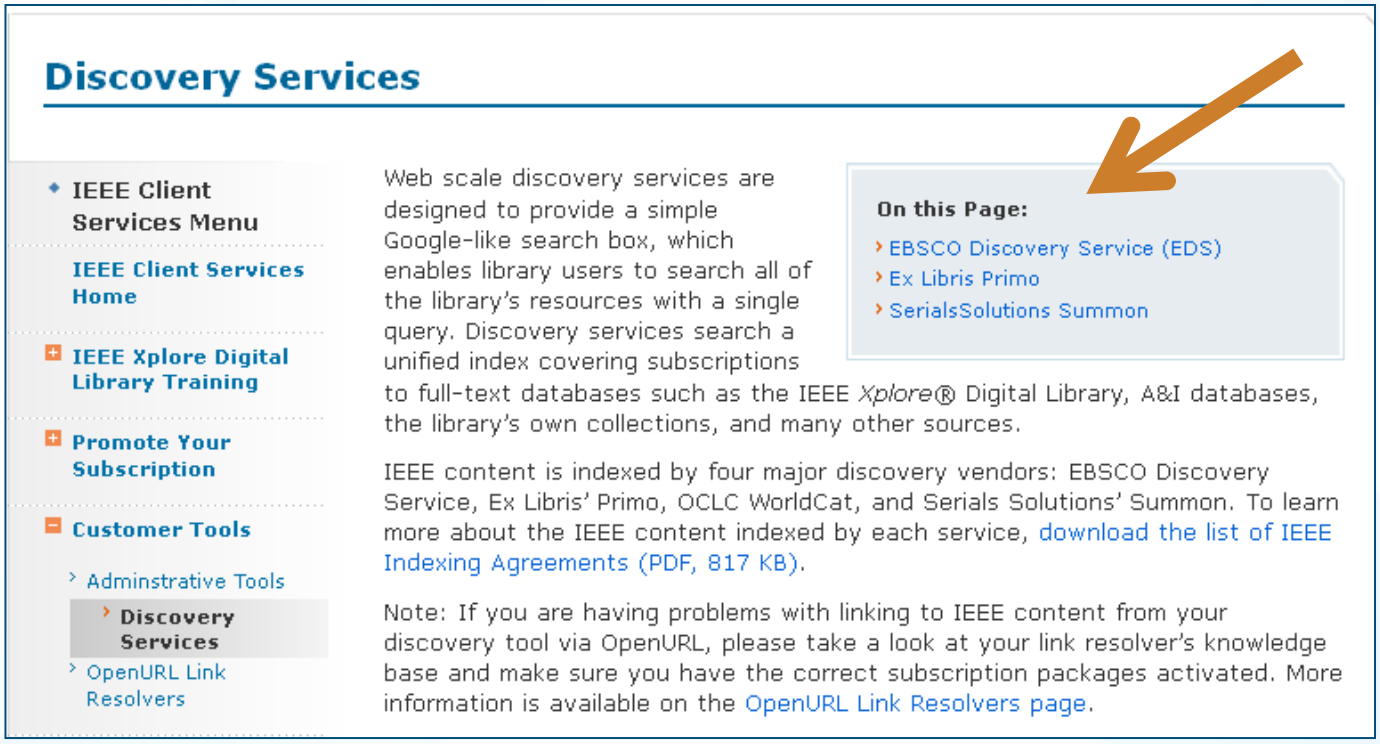

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Thank-you!

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Appendix

Additional information for reference

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- World's largest technical membership association with nearly 429,000 members in over 162 countries
- Not for profit organization with tagline "Advancing Technology For Humanity"
- Four Core areas of activity
  - **Membership organization**
  - **Conference organizer**
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  - **Publishing company**

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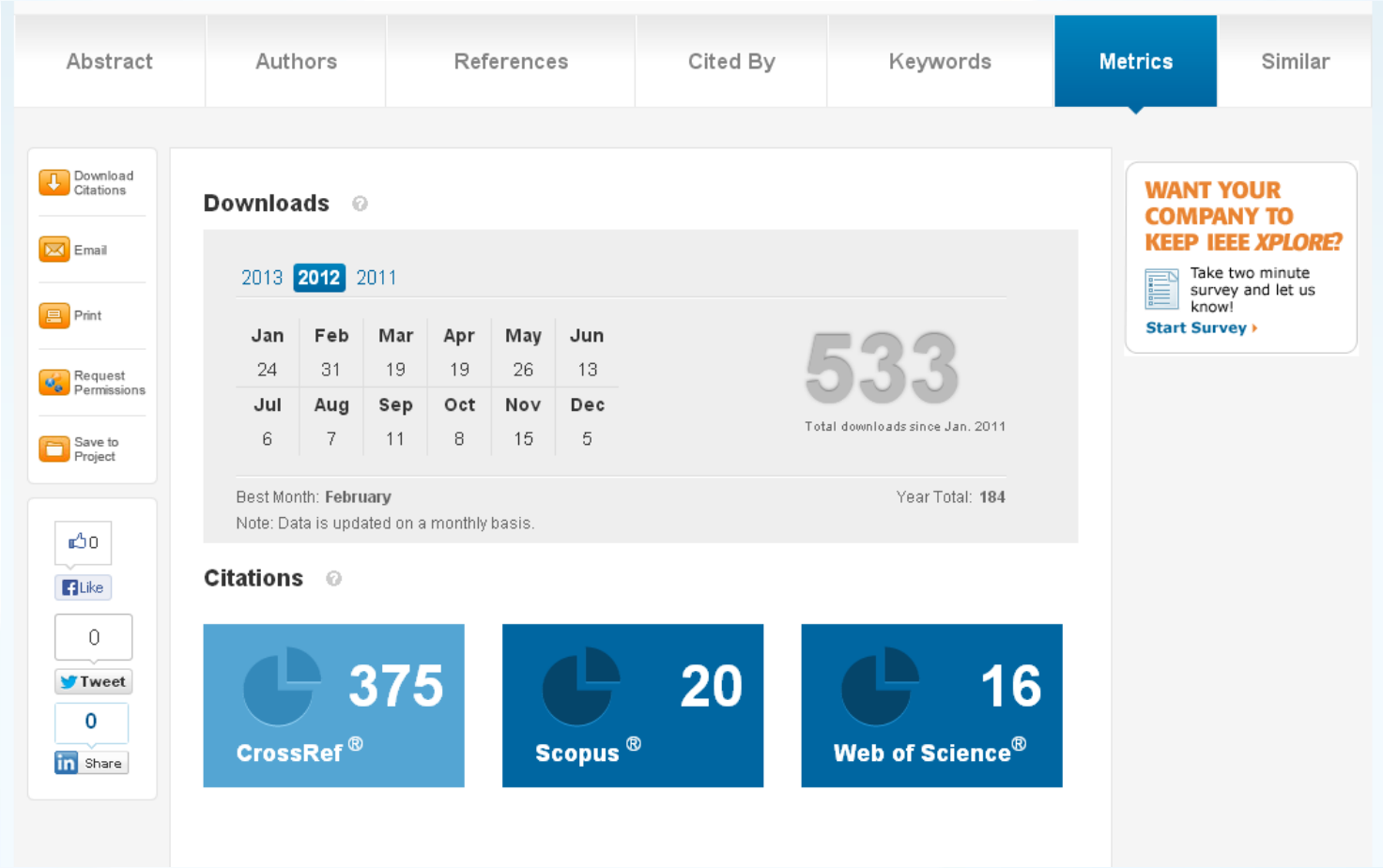

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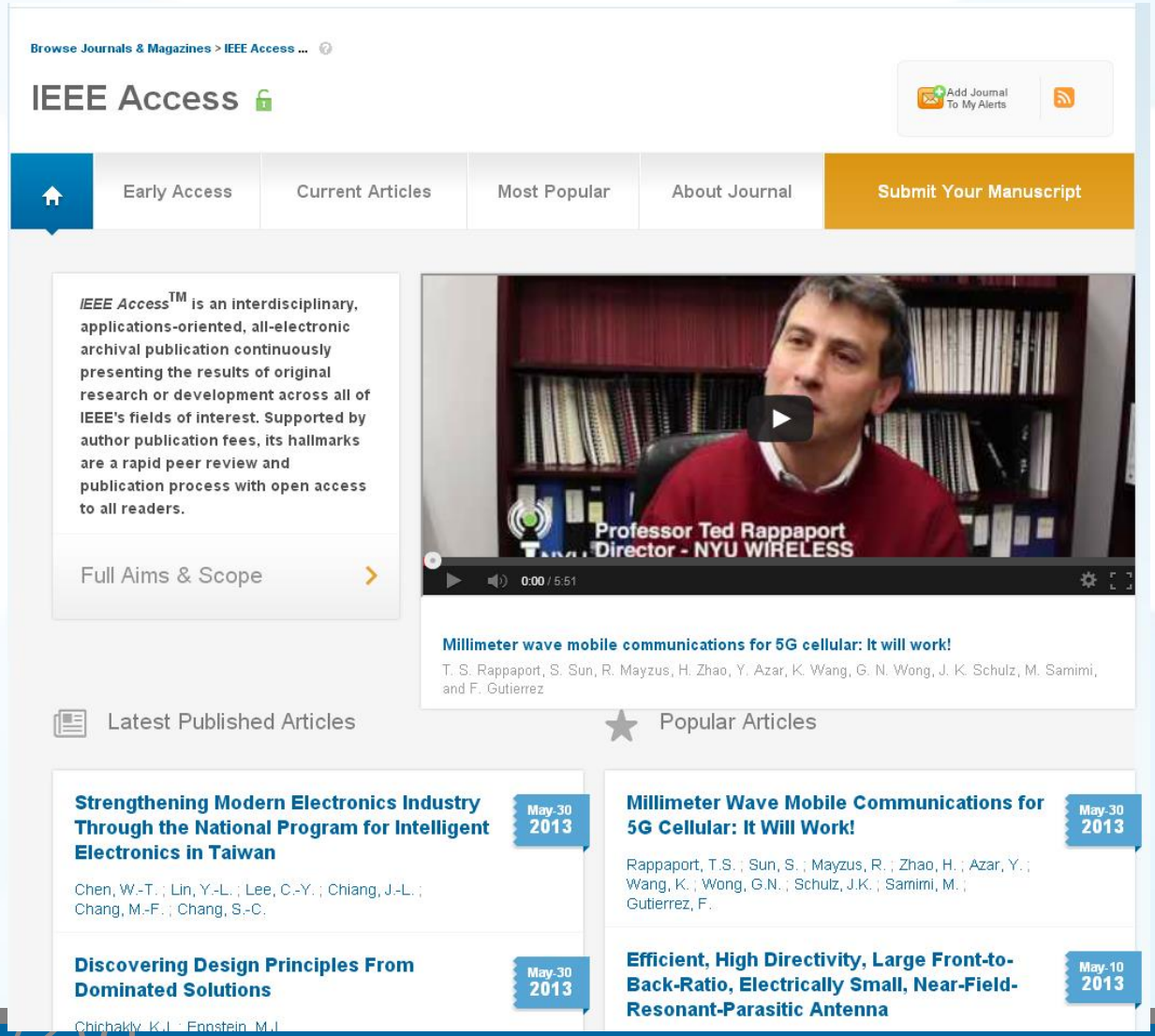

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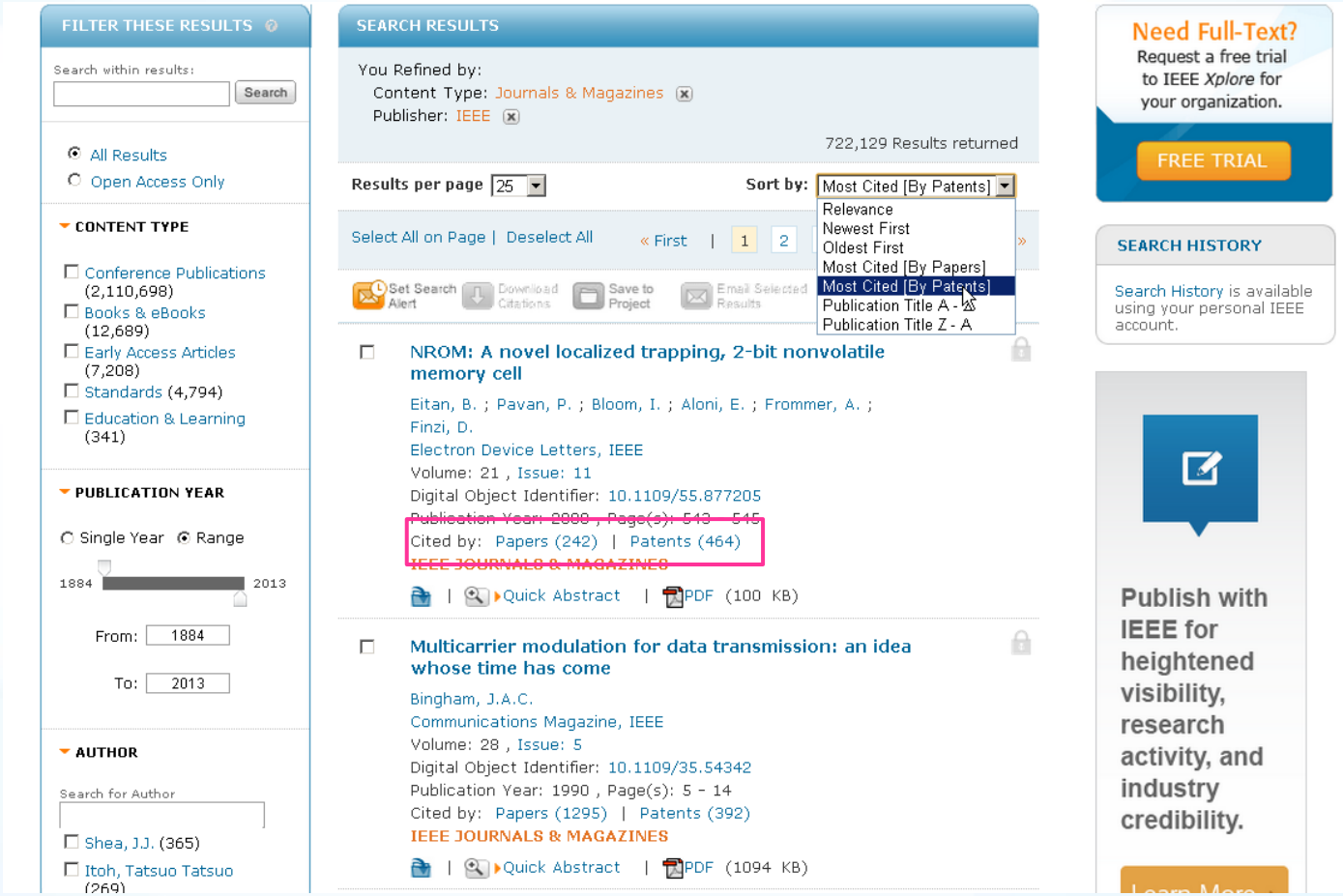

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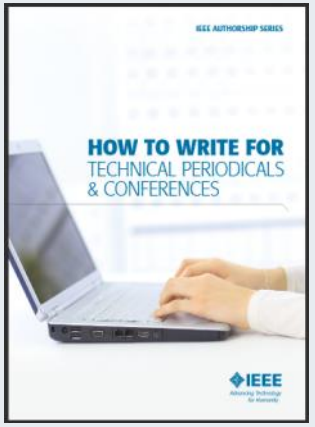

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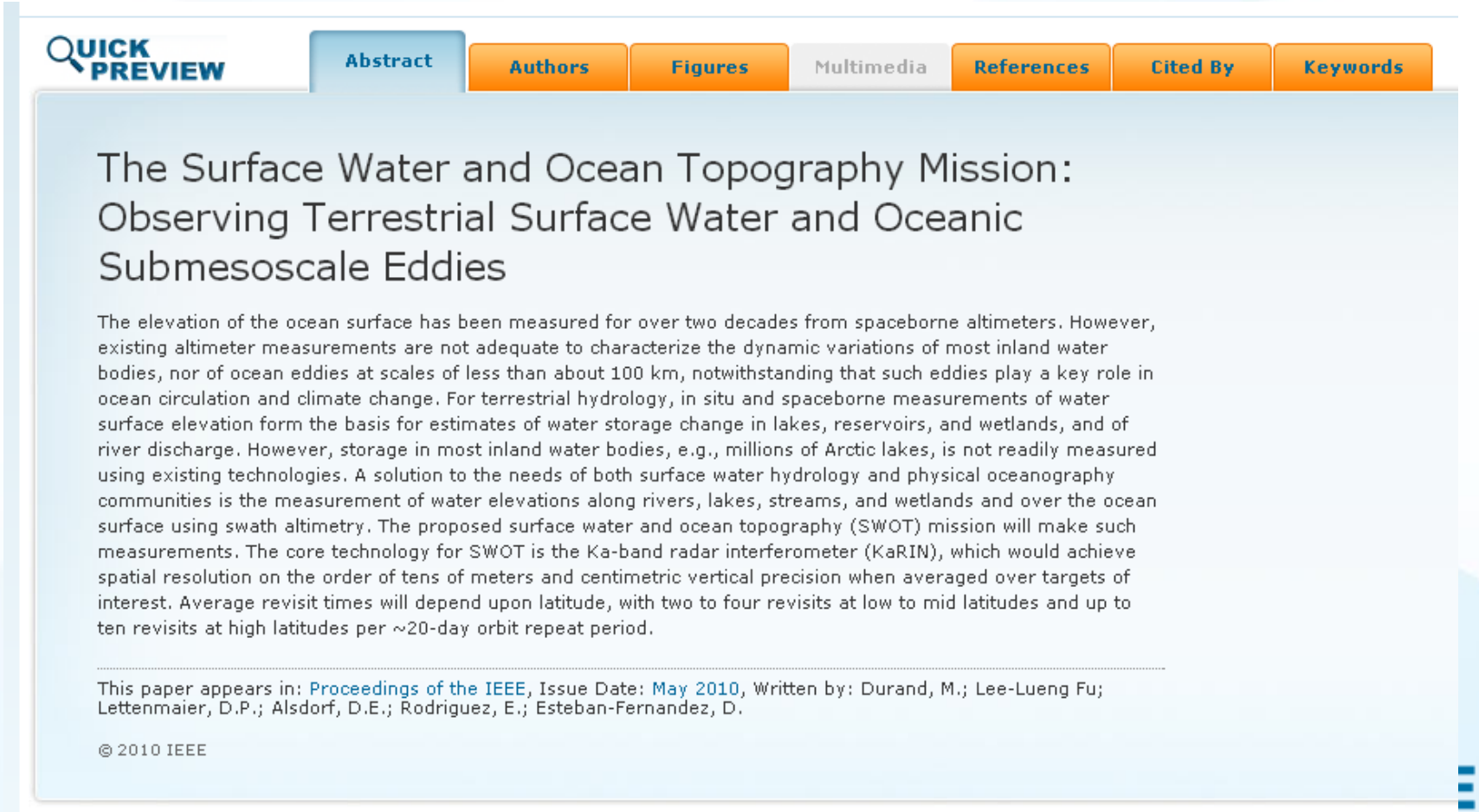

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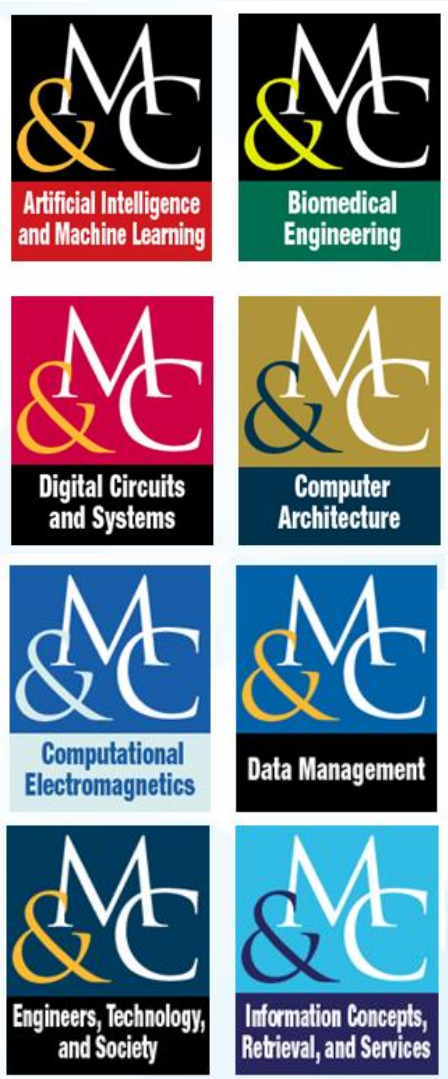

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IEEE 802 Series—IEEE Standard for Ethernet

IEEE 3000 Standards Collection™—Formerly the IEEE Color Books®, this collection will reorganize the 13 Color Books into approximately 70 "dot" standards covering specific technical topics on all facets of industrial and commercial power systems.

IEEE 81-2012™—IEEE Guide for Measuring Earth Resistivity, Ground Impedance, and Earth Surface Potentials of a Grounding System

2012 National Electrical Safety Code® (NESC®)—Sets the ground rules for practical safeguarding of persons during the installation, operation, or maintenance of electric supply and communications lines and associated equipment.

IEEE 43™—IEEE Recommended Practice for Testing Insulation Resistance of Electric Machinery

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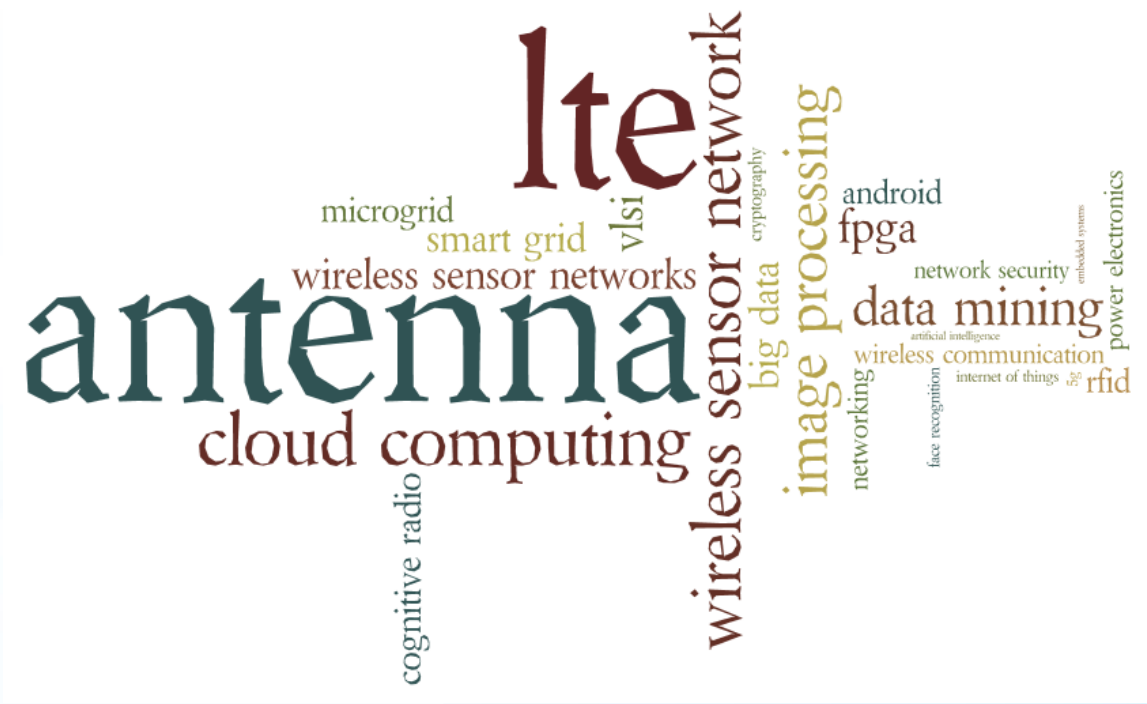
Rank	Search Term
1	cloud computing
2	image processing
3	data mining
4	big data
5	network security
6	wireless sensor networks
7	android
8	smart grid
9	power electronics
10	antenna
11	internet of things
12	vlsi
13	networking
14	artificial intelligence
15	wireless communication
16	5g
17	cryptography
18	rfid
19	cognitive radio
20	fpga
21	embedded systems
22	wireless sensor network
23	microgrid
24	face recognition
25	lte



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Key Themes Defining The Future

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- Ease of data accessibility
- Outside & inside innovation
- New applications and tools

"Segment of One" User Experiences

- Know who I am
- Know what I want
- Give it to me the way I want

Collaboration and Networking

- Help me connect with others
- Give me access to experts
- Help me be more productive

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How does IEEE listen to its customers?

- IEEE Library Advisory Council
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- CSM trainings at customer sites
- Questions & requests to CSMs
- Engineering and library conferences
- Customer surveys
- Volunteer leadership

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IEEE & Data Conservancy

- In May 2014, the Data Conservancy, in partnership with IEEE and Portico, have been awarded a grant to link publications with data.
- Now a significant grant from the Alfred P. Sloan Foundation will support the creation of a service to do just that.
- This service will help preserve the myriad relationships that often exist between and among scholarly and scientific publications and associated datasets.

"We believe that the models developed as a result of this project will enable new forms of scholarly communication, and thus help to set the stage for the future of research and digital publishing."

- Sayeed Choudhury, associate dean for research data management and Hodson director of the Digital Research and Curation Center at the Sheridan Libraries of Johns Hopkins University

Read the Press Release:
http://www.portico.org/digital-preservation/news-events/news/the-data-conservancy-ieee-and-portico-receive-alfred-p-sloan-foundation-grant-to-connect-publications-and-their-linked-data

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IEEE and ORCID

- ORCID is an open, non-profit, community-driven effort to create and maintain a registry of **unique researcher** identifiers and a transparent method of linking research activities and outputs to these identifiers.
- It is a hub that **connects researchers and research** through the embedding of ORCID identifiers in key workflows, such as research profile maintenance, manuscript submissions, grant applications, and patent applications.
- ORCID provides two core functions:
  - (1) a registry to obtain a unique identifier and manage a record of activities, and
  - (2) APIs that support system-to-system communication and authentication

IEEE and ORCID

- IEEE is working actively with ORCID on the following collaborations and development projects:
  - IEEE Member Profile Management Portal
  - IEEE Author Gateway
  - IEEE Conference Submission Systems
  - IEEE *Xplore* Digital Library – Author Publication Page
- All projects at various stages of development. For more info, see Renny Guida, IEEE Dir. of Prod Mgmt. (r.guida@ieee.org)

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The 2014 JCR study, released in July 2015, shows that IEEE publications continue to rank at the top in citations on technology.

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- **Internet of Things** (WF-IoT), 2014 IEEE World Forum on
- **Humanitarian Technology** Conference, (IHTC), 2014 IEEE Canada International
- Aerospace Electronics and Remote Sensing Technology (ICARES), 2014 IEEE International Conference on
- Antenna Measurements & Applications (CAMA), 2014 IEEE Conference on
- Consumer Electronics, Taiwan (ICCE-TW), 2014 IEEE International Conference on
- Energy Conversion (CENCON), 2014 IEEE Conference on
- Ethics in Science, Technology and Engineering, 2014 IEEE International Symposium on
- **Transportation Electrification** Asia-Pacific (ITEC Asia-Pacific), 2014 IEEE Conference and Expo
- **Intelligent Energy** and Power Systems (IEPS), 2014 IEEE International Conference on
- Quantum Optics Workshop (QOW), 2014
- Sensor Systems for a Changing Ocean (SSCO), 2014 IEEE
- Wireless and Mobile, 2014 IEEE Asia Pacific Conference on
- Industrial Engineering and Information Technology (IEIT), 2014 International Conference on
- Guidance, Navigation and Control Conference (CGNCC), 2014 IEEE Chinese

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Examples of New IEEE Standards in 2014

IEEE 802®–2014—IEEE Standard for **Local and Metropolitan Area Networks**: Overview and Architecture

IEEE 1127™–2013—IEEE Guide for the Design, Construction, and Operation of **Electric Power Substations** for Community Acceptance and Environmental Compatibility

IEEE 1361™–2014 —IEEE Guide for Selecting, Charging, Testing, and Evaluating Lead-Acid Batteries Used in Stand-Alone **Photovoltaic (PV) Systems**

IEEE 1609.0™–2013 - IEEE Guide for **Wireless Access in Vehicular Environments** (WAVE) – Architecture

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